

Keys needs in the technology roadmap for superconductor electronics

D. Scott Holmes

International Roadmap for Devices and Systems (IRDS)

2022-10-24 ASC **1EOr2B-01**

Keys needs in the technology roadmap for superconductor electronics

Abstract

A technology roadmap for superconductor electronics is under development within the framework of the International Roadmap for Devices and Systems (IRDS). Significant technology improvements are required for superconductor electronics to meet the needs expected for applications such as quantum computing, artificial intelligence, or large-scale digital computing. Metrics for improvement include circuit density, chip or system complexity, and energy efficiency. Key needs are identified in areas including fabrication processes, devices, logic families, and system architectures. Metrics and methods are under development to evaluate potential solutions for the key needs. A challenge is that evaluation of overall benefit often requires large-circuit or system-level modeling, which can be difficult without the necessary electronic design automation (EDA) tools.

Presenter: D. Scott Holmes

Applied Superconductivity Conference

2022 October 24–28, Honolulu, Hawaii, USA

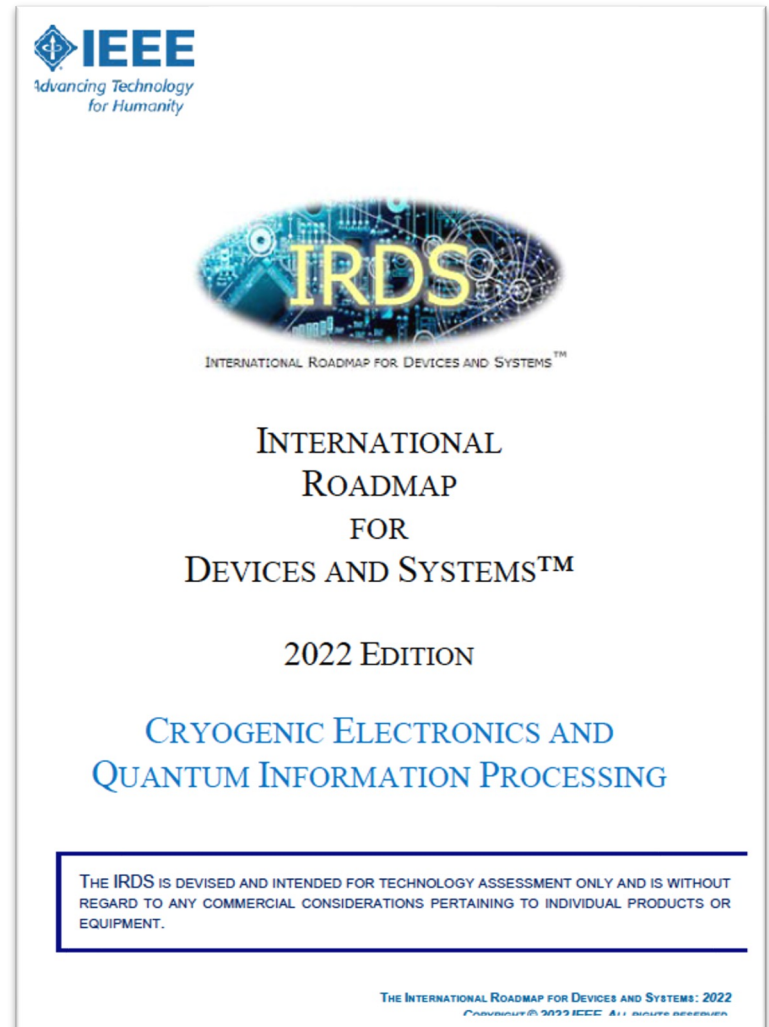
<https://www.appliedsuperconductivity.org/asc2022/>



2022 IRDS CEQIP summary

- Coverage
 - Superconductor Electronics (SCE)
 - Cryogenic Semiconductor Electronics
 - Quantum Information Processing (QIP)
- Key Messages from the 2022 report
 - SCE: Partial roadmaps
 - QC: Not yet ready for roadmaps
- Summary slides:
 - Difficult Challenges
 - Technology Requirements
 - Potential Solutions
- Updates
 - New Technology Requirements
 - Breakthroughs in Technology, Research
 - New Disruptors
 - Potential Solutions
- Conclusions and Recommendations

Available:
<https://irds.ieee.org/editions>



2023 CEQIP Members



| Name | Area | Organization | Region |
|-------------------------|----------------------------|--|----------|
| Byun, Ilkwon | Cryo-Semi, QIP-QC | Seoul National University, Korea | Asia |
| Cuthbert, Michael | Cryo, QIP | National Quantum Computing Centre, UK | Europe |
| DeBenedictis, Erik | QIP-QC | Zettaflops, USA | Americas |
| Fagaly, Bob | SCE-App | Honeywell (retired), USA | Americas |
| Fagas, Giorgios | QIP | Tyndall National Institute, Ireland | Europe |
| Febvre, Pascal | SCE-Fab | Université Savoie Mont Blanc, France | Europe |
| Filippov, Timur | SCE-Log | Hypres, USA | Americas |
| Fourie, Coenrad | SCE-EDA | Stellenbosch University, South Africa | Africa |
| Frank, Mike | SCE-Log, -Rmap | Sandia National Laboratories, USA | Americas |
| Gupta, Deep | SCE, Cryo-Semi | SEACORP, USA | Americas |
| Herr, Anna | SCE-Logic, -Rmap | IMEC, Belgium | Europe |
| Holmes, D Scott [Chair] | SCE, Cryo-Semi, QIP | Booz Allen Hamilton, USA | Americas |
| Humble, Travis | QIP-QC | Oak Ridge National Laboratory, USA | Americas |
| Leese de Escobar, Anna | SCE-App, -Bench | Navy NIWC-PAC, USA (retired) | Americas |
| Min, Dongmoon | Cryo-Semi, QIP-QC | Seoul National University, Korea | Asia |
| Mueller, Peter | QIP-QC-SC | IBM Zürich, Switzerland | Europe |
| Mukhanov, Oleg | QIP-QC, SCE-Log | Seeqc, USA | Americas |
| Nemoto, Kae | QIP | The National Institute of Informatics (NII), Japan | Asia |
| Papa Rao, Satyavolu | SCE-Fab, QIP | SUNY Polytechnic, USA | Americas |
| Pelucchi, Emanuele | QIP-QC | Tyndall National Institute, Ireland | Europe |
| Plourde, Britton | QIP | Syracuse University, USA | Americas |
| Soloviev, Igor | SCE | Lomonosov Moscow State University, Russia | Europe |
| Tzimpragos, George | SCE-Logic, -Metrics, -Rmap | University of Michigan, USA | Americas |
| Vogelsang, Thomas | Cryo-Semi | Rambus, Inc., USA | Americas |
| Weides, Martin | SCE, QIP | University of Glasgow, UK | Europe |
| Yoshikawa, Noboyuki | SCE-Log, -Bench | Yokohama National University, Japan | Asia |
| You, Lixing | SCE | SIMIT, CAS, China | Asia |

Additions for 2023

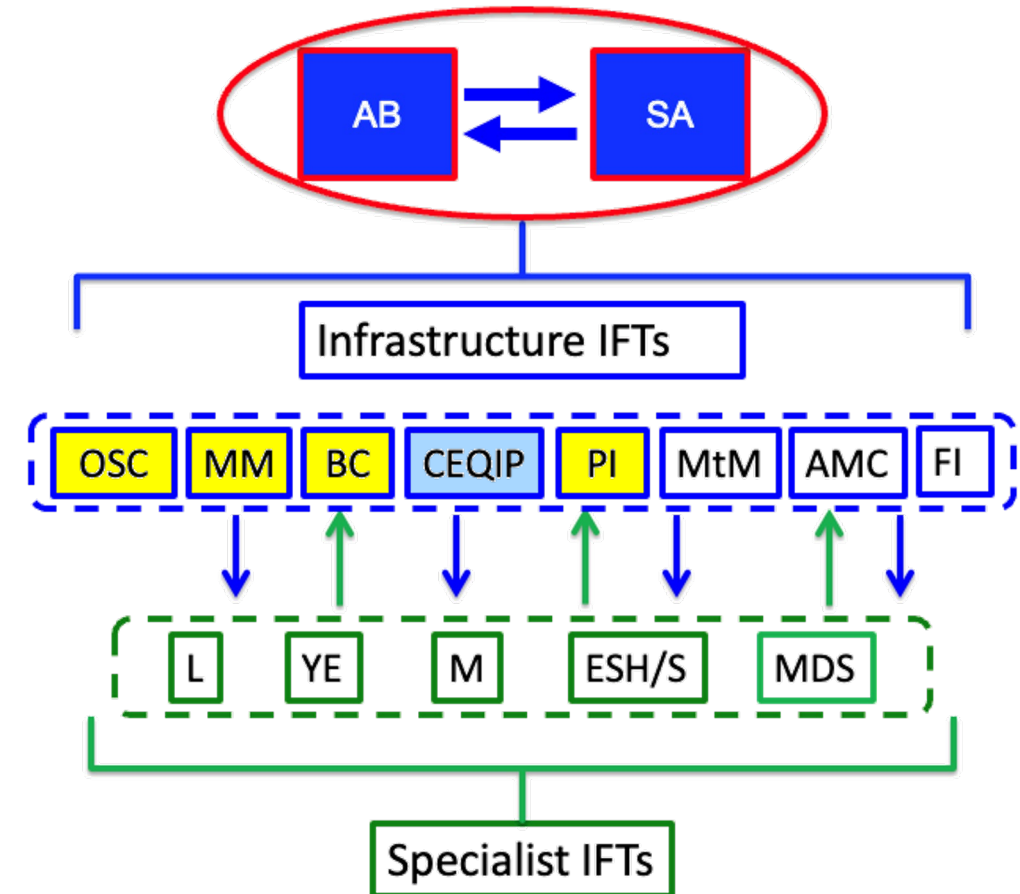
13: Americas
9: Europe + Africa
5: Asia

IRDS IFT Cross-team and Collaborative Alignments



IFT: International Focus Team

- CEQIP primary interactions with IRDS teams
 - **AB**: Application Benchmarking
 - **SA**: Systems and Architectures
 - **BC**: Beyond CMOS
 - **MM**: More Moore
 - **OSC**: Outside System Connectivity
 - **PI**: Packaging and Integration
- External Organizations (contact person)
 - IEEE Quantum Initiative (Erik DeBenedictis)
 - QED-C: Quantum Economic Development Consortium (Erik DeBenedictis)
 - UK National Quantum Computing Centre Roadmap (Michael Cuthbert)



IFT structure of the IRDS

2022 Report: Superconductor Electronics (SCE)



- 2.1. Introduction to SCE
- 2.2. Applications and Market Drivers for SCE
 - 2.2.1. Cloud (Digital Computing)
 - 2.2.2. Measurement and Calibration Systems
 - 2.2.3. Communications
 - 2.2.4. Quantum Computing: Control and Readout
- 2.3. Present Status for SCE
 - 2.3.1. Logic
 - 2.3.2. Memory
 - 2.3.3. Switching Devices
 - 2.3.4. Other Circuit Elements for SCE
 - 2.3.5. Architectures and Applications
 - 2.3.6. Fabrication for SCE
 - 2.3.7. Electronic Design Automation (EDA) for SCE
 - 2.3.8. Packaging and Testing for SCE
 - 2.3.9. Interconnects for SCE
 - 2.3.10. Refrigeration
- 2.4. Benchmarking and Metrics for SCE
 - 2.4.1. Device and Circuit Benchmarking
 - 2.4.2. Scaling of Devices and Circuits
 - 2.4.2. System and Application Benchmarking
- 2.5. Active Research Questions for SCE
- 2.6. Roadmaps for SCE

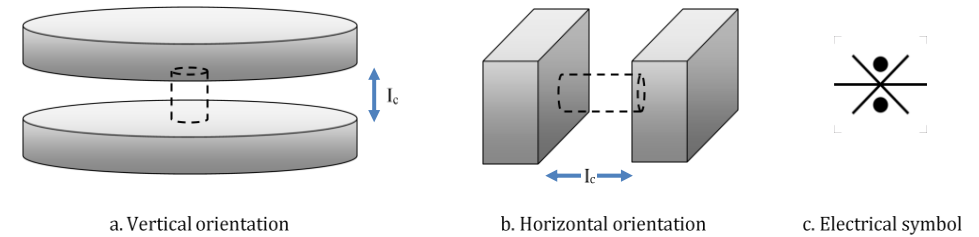


Figure CEQIP-1. Josephson Junction Device Structures

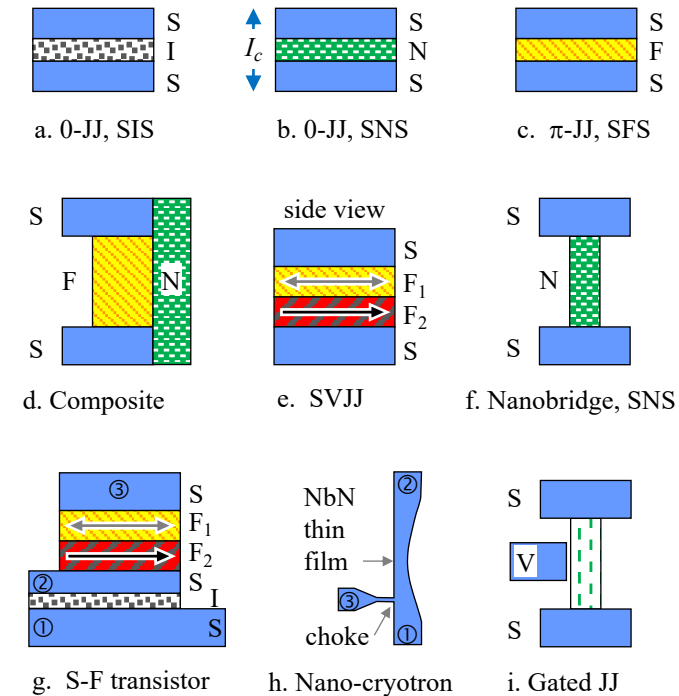


Figure CEQIP-3. Superconductor (S) switching devices



2022 SCE Roadmap Status

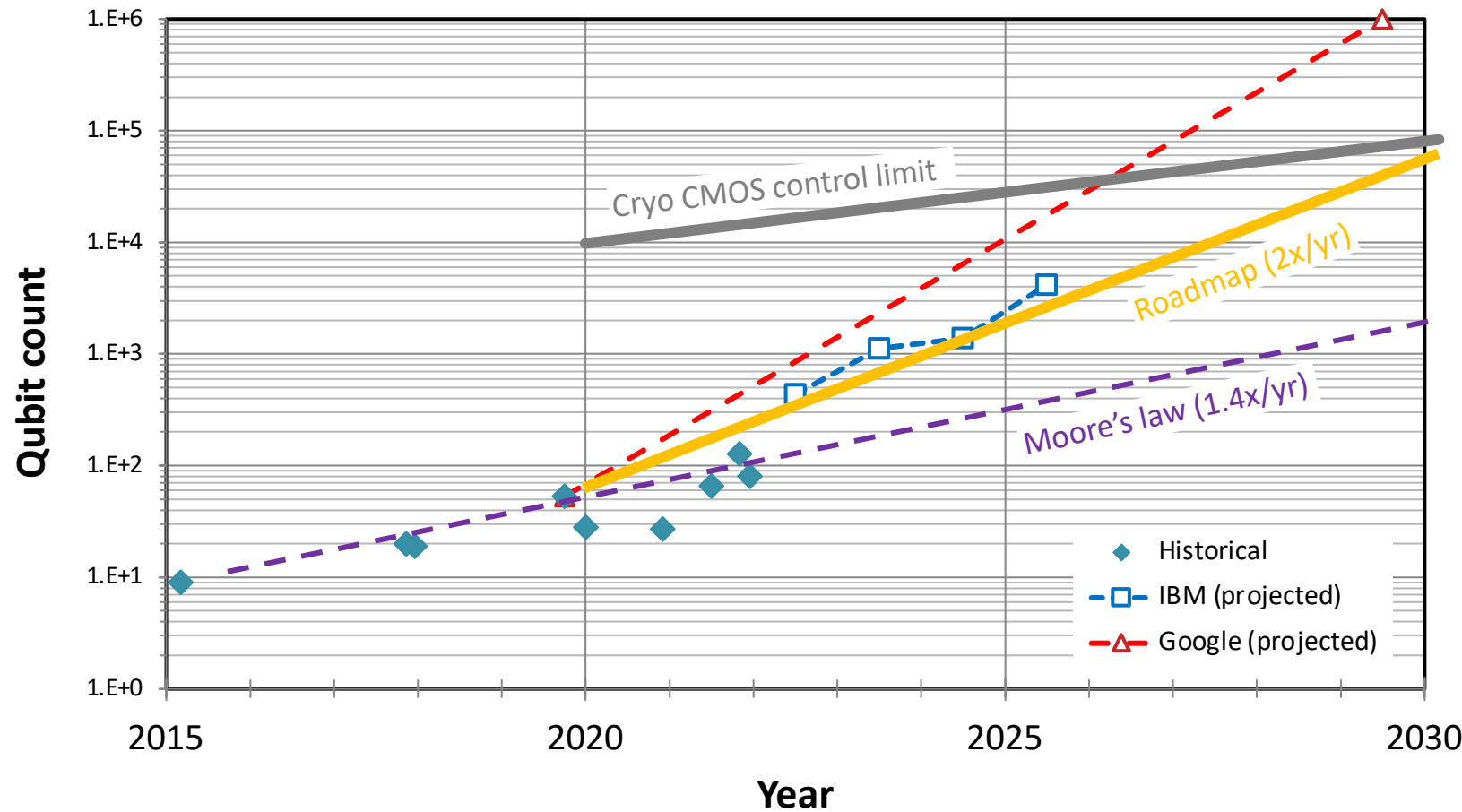
- Status summary
 - SCE is a developing technology with a small market and big promise
 - Quantum information processing (QIP) is currently a driver
 - Logic: Many competing approaches
 - Memory: Little available; no clear solutions
 - Fabrication: Research + some commercial (slow progress)
- Technology roadmap benefits
 - Provide metrics and goals to guide effort and to evaluate alternatives
 - Identify key needs for research and development

Application: Superconducting Quantum Computing



Superconducting qubit roadmap

~ 2.7x/year



Control:

- Superconductor ~ 4 K
- Semiconductor ~ 4 K
- External ~ 300 K (RT)

2023 Superconducting QC Roadmap, First Cut



| Metric | 2020 | 2022 | 2024 | 2026 | 2028 | 2030 | 2032 |
|--|-----------|--------------------|-----------|----------|---------|---------|--------|
| Qubit growth per year | 2x | 2x | 2x | 2x | 2x | 2x | 2x |
| Qubit count | 5.5e+1 | 2.2e+2 | 8.8e+2 | 3.5e+3 | 1.4e+4 | 5.6e+4 | 2.2e+5 |
| Qubit type | Transmon | Transmon | Transmon | Transmon | ? | ? | ? |
| Qubit lifetime T1, med. [ms] | 0.5 | | | | | 10 | |
| 2 qubit gate error rate, median (p_2Q) | 1.0e-2 | In Progress | | | | 1.0e-4 | |
| Gate depth (1/p_2Q) | 1.0e+2 | | | | | 1.0e+4 | |
| Error correction code | Surface | Surface | Surface | Surface | Surface | Surface | ? |
| Phys. qubits per logical qubit | | | | 1000 | 1000 | 1000 | 1000 |
| Logical qubit count | | | | 3 | 14 | 56 | 220 |
| Logical qubit error rate | | | | | | 1.0e-15 | |
| Control type, temp. [K] | CMOS, 300 | CMOS, 300 | CMOS, 300 | CMOS, 4 | CMOS, 4 | CMOS, 4 | SCE, 4 |
| SCE control complexity [JJ] | 1.1e+5 | 4.5e+5 | 1.8e+6 | 7.2e+6 | 2.9e+7 | 1.2e+8 | 4.6e+8 |

2021 DIFFICULT CHALLENGES (SCE)



Technology Road Blocks...Highlight gaps and showstoppers, possible disconnects within the roadmap

- Near term (2020-2027)
 - **EDA tools for superconductor electronics**
 - EDA tools for CMOS are not adequate for SCE. Inductance is critical in superconducting circuits and connecting wires must have inductance values within a specified range. Circuit simulators and timing analysis must be modified.
 - **PDKs for fabrication processes**
 - Complete process design kits (PDKs) are needed for fabrication processes for superconductor electronics.
 - Yield improvement of circuits with > 1 M Josephson junctions (switching devices)
 - Variation in device parameters reduces the operating margins of circuits. Needed is better process control, better device designs, or circuit designs that tolerate or compensate for device variability.
- Long term (2028-2035)
 - Temperature limits compatible with CMOS fabrication processes
 - Nb/Al-AIO_x/Nb Josephson junctions are sensitive to temperature. Temperatures are currently limited to < 200 °C, which requires different processes than CMOS technology, which has a limit of 400 °C.
 - Optical input/output (I/O)
 - Communication with room-temperature systems and networks will require a high-data-rate I/O, but interconnection cannot introduce significant heat into a low-temperature environment. Optical fiber digital links would be ideal, but efficient SFQ-to-optical converters must be developed.
 - Magnetic materials fabrication process integration
 - Magnetic materials are desired to make both memory and passive devices. Integrating magnetic materials into foundry processes will be difficult.



2022 Difficult Challenges (Near-term) for SCE

Technology roadblocks, gaps, and possible disconnects within the roadmap

| <i>Near-Term Challenges: 2022–2029</i> | <i>Summary of Issues (why is it a challenge?)</i> |
|--|---|
| Logic (current implementations) | <ul style="list-style-type: none"> • Many competing approaches • Sensitivity to magnetic fields and fabrication variation • Supply current is mostly spent biasing junctions • Power and clock pulse distribution add complexity and jitter • Scalable to solve big problems (DSP, AI, QC, HPC) |
| Memory | <ul style="list-style-type: none"> • Density is too low for single-flux-quantum memory (like SRAM) • Multiplexing is difficult for single-flux-quantum logic • New materials and processes add cost |
| Phase shift elements | <ul style="list-style-type: none"> • Present approach (external supply current through inductors) does not scale. DC bias is $\sim 0.7 I_c$ per junction, so chip supply current becomes too large for > 1 million junctions. Inductors require shielding. • Phase batteries such as pi junctions require new materials, device layer. |
| NbN or NbTiN fabrication process | <ul style="list-style-type: none"> • NbN and NbTiN now deposited by reactive sputtering, which is difficult to make uniform across a 200 mm or 300 mm diameter wafer • CVD or ALD processes will require development |



2022 Difficult Challenges (Long-term) for SCE

Technology roadblocks, gaps, and possible disconnects within the roadmap

| <i>Long-Term Challenges: 2030–2037</i> | <i>Summary of Issues (why is it a challenge?)</i> |
|--|---|
| Switching device scalable below 200 nm | <ul style="list-style-type: none"> Nb/Al-AlO_x/Nb Josephson junctions are almost good enough Alternatives will require different materials and fabrication processes, possibly including magnetic materials |
| 3-terminal switching device | <ul style="list-style-type: none"> Small available flux $\sim 2 \text{ mA}\cdot\text{pH}$ or voltage $\sim 1 \text{ mV}$ Fabrication more difficult than the traditional tri-layer device |
| Integrated circuit fabrication processes | <ul style="list-style-type: none"> Foundries for commercial production now process 200 mm or smaller wafers using equipment lacking state-of-the-art capability. Temperatures are currently limited to $< 200 \text{ }^\circ\text{C}$, which requires different processes than CMOS technology, which has a limit of $400 \text{ }^\circ\text{C}$. Circuit approaches and fabrication processes are interdependent, requiring co-development. Magnetic materials need to be added. |
| Optical input/output (I/O) | <ul style="list-style-type: none"> Heat budget in the low-temperature environment is very low. Optical data links require development of efficient SFQ-to-optical converters. |

- But can these wait?



Key Need Areas

for superconductor electronics (SCE)

1. Power supply
2. Sensitivity to external magnetic fields, currents, and trapped flux
3. Area reduction
4. Logic
5. Memory
6. Fabrication for scale

Other

1. Design tools
2. Testing



1. Power Supply

Approaches for improvement:

1. DC Serial biasing
2. AC to DC
3. AC power distribution

DC Supply Current to Bias JJs



Biasing sets signal flow direction →

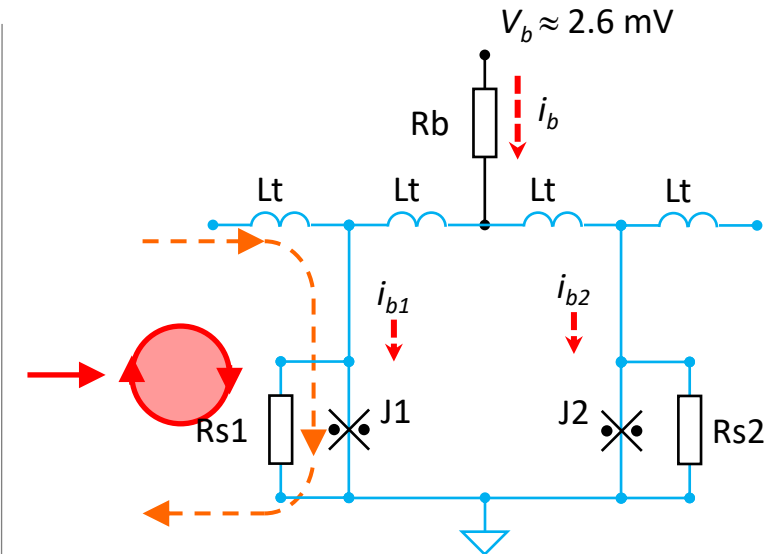
- $I_C \approx 100 \mu\text{A}$ (constraints: thermal noise, switching energy)
- $K_0 \approx 0.7$ (bias current ratio, $K_0 \equiv i/I_C$)
- $\alpha \approx 0.5$ (fraction of biased junctions)

- Bias current for 1 million junctions in parallel?

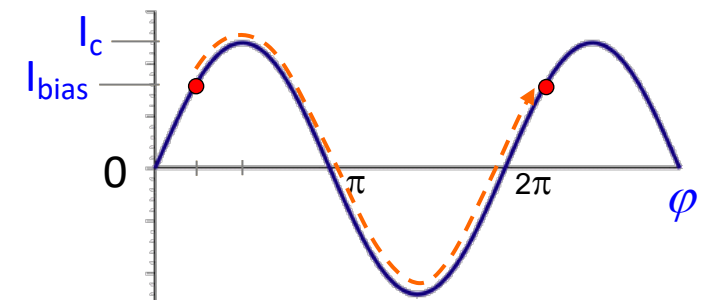
$$I_b = N I_C K_0 \alpha = (1e+6)(100e-6)(0.7)(0.5) = \mathbf{35 \text{ A}}$$

- Way too much current and not nearly enough junctions!

▶ Traditional DC biasing will not scale.



Junction bias in RSFQ



$$i = I_C \sin(\phi)$$

Supply Current: Recycling

DC bias current

- Pass DC bias current through a series of N ground plane 'islands'
 - $N = 16$ demonstrated with highly regular circuits (shift registers) [1]
- Advantages
 - $N \times$ bias current reduction
- Disadvantages
 - Clock, data nets also require separation
 - Area multiplier $\approx 1.5 \times$ (??)
 - JJ return current paths can affect margins
 - Complexity of balancing island currents
 - Capacitive coupling between floating islands
 - Ground plane gap shields needed

▶ Perhaps the first thing to try

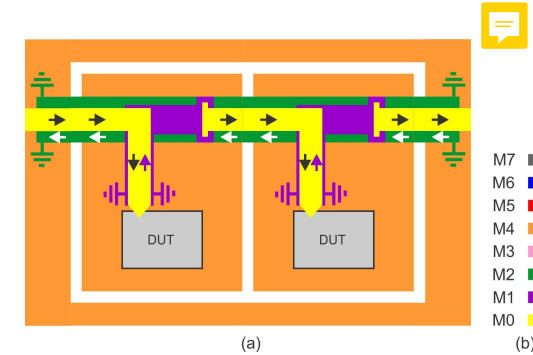
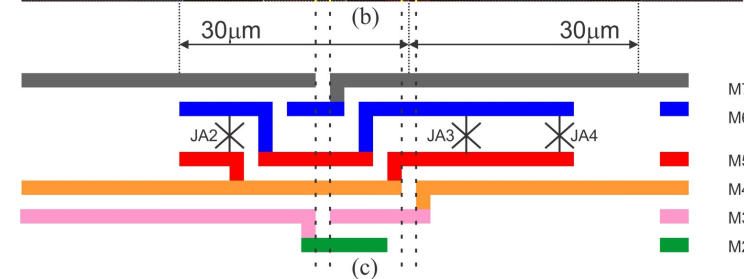
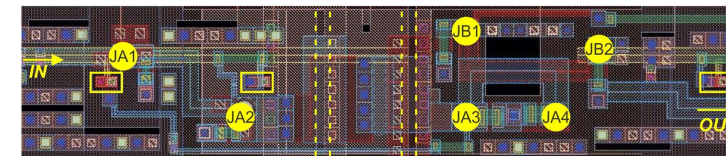
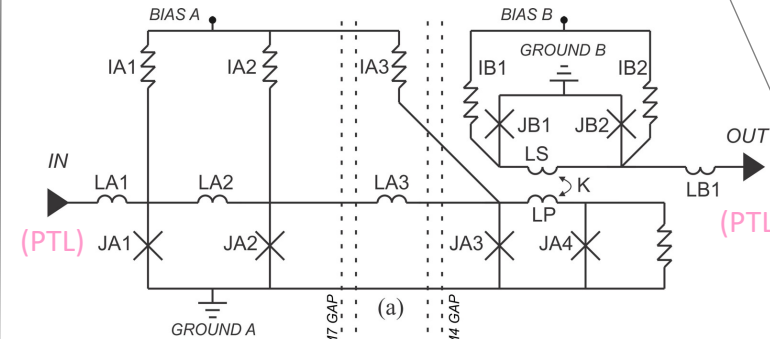


Fig. 1. Grapevine distribution of DC bias currents. [2]

Fig. 2. Driver-receiver pair (DRP) to transfer clock and data pulses between islands. [2]

[1] Semenov+, "Current recycling: New results," 2019, doi: [10.1109/TASC.2019.2904961](https://doi.org/10.1109/TASC.2019.2904961)

[2] Shukla+, "Serial biasing technique for electronic design automation in RSFQ circuits," 2022, doi: [10.1109/TASC.2022.3214767](https://doi.org/10.1109/TASC.2022.3214767)



Supply Current: AC/DC Conversion

- Convert AC to DC on chip using rectifiers [1, 2] or local flux biasing [3]
- Best used with logic cells that require AC or **no** bias current
- Advantages
 - AC supply to converters in series, so can supply more cells ($\approx 100\times$?)
- Disadvantages
 - Complexity, area overhead factor $\approx 2\times$ (?)
 - Transformers don't scale well
 - $f_{AC} > f_{clock}$ for best energy efficiency
 - Need to design more logic cells that use AC or no bias current

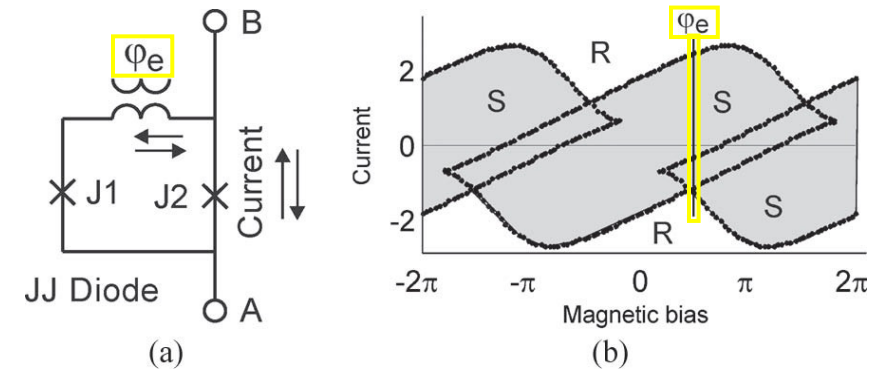


Fig. 1. Rectifier based on a magnetically biased SQUID. [1]

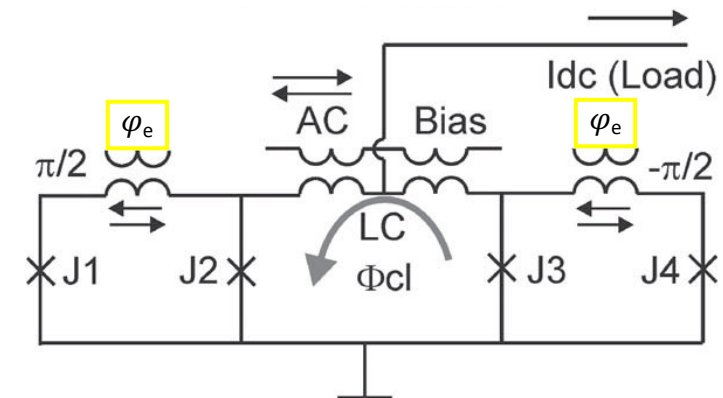


Fig. 2. AC/DC converter. [1]

[1] Semenov+, 2015, doi: [10.1109/TASC.2014.2382665](https://doi.org/10.1109/TASC.2014.2382665)

[2] Semenov+, 2017, doi: [10.1109/TASC.2017.2669585](https://doi.org/10.1109/TASC.2017.2669585)

[3] Asada+, 2021, doi: [10.1088/1361-6668/abf23a](https://doi.org/10.1088/1361-6668/abf23a)



Supply Current: AC/SFQ Conversion

- Better: Convert AC to SFQ (not DC) on chip using rectifiers
- Best used with logic cells that require AC or **no** bias current
- Advantages
 - AC supply to converters in series, so can supply more cells ($\approx 1000\times$?)
- Disadvantages
 - Complexity, area overhead factor $\approx 2\times$ (?)
 - Transformers don't scale well
 - $f_{AC} > f_{clock}$ for best energy efficiency
 - Need to design more logic cells that use AC or no bias current

► Needs further investigation

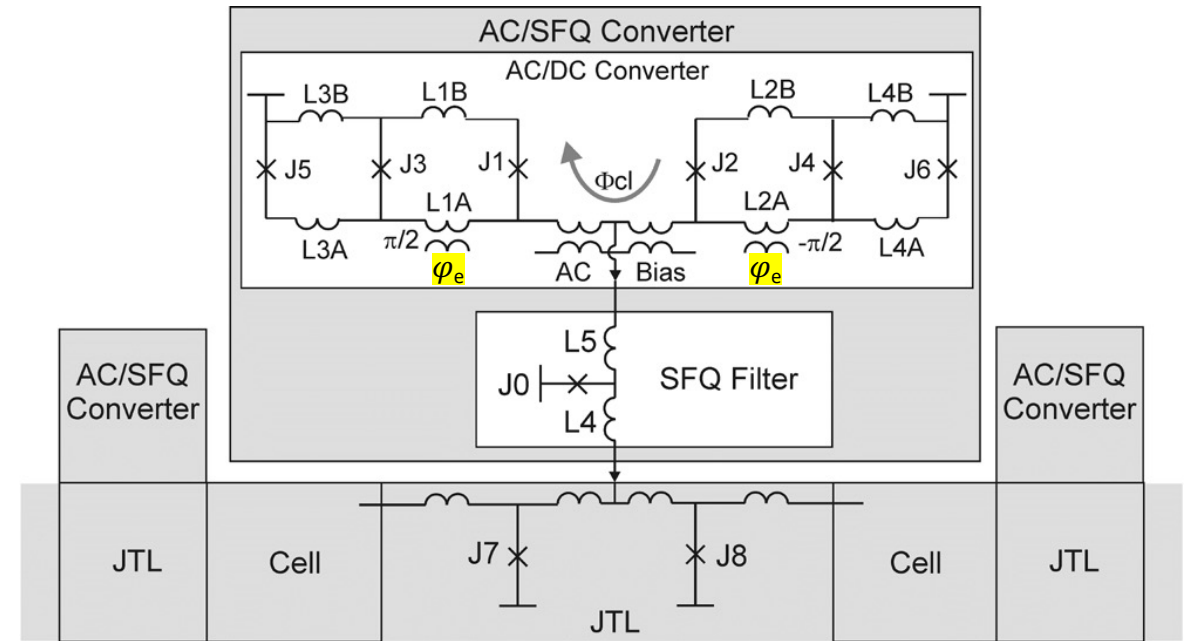


Fig. 3a. AC/SFQ converter supplying a JTL. [1]

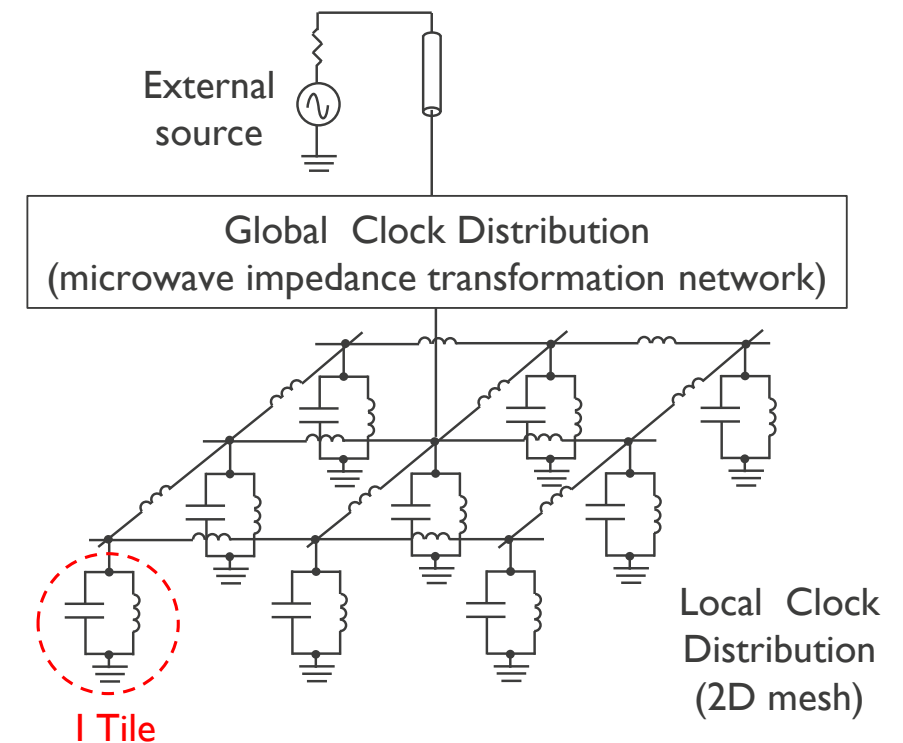
[1] Semenov+, 2021, doi: [10.1109/TASC.2021.3067231](https://doi.org/10.1109/TASC.2021.3067231)



AC Power Distribution

Design concept for large-scale clock distribution

- Local storage of power and clock signal in high-Q LC-resonators
 - 1 resonator per tile
- 2D mesh of LC resonators has a zero-order mode
 - Clock signal distribution over large area with only small amplitude and phase variation
- 30 GHz design with 400 M taps/cm²



▶ ASC 2022 Oct 26 14:30, **3EPo2B-06** [E11], Q. Herr



2. Sensitivity to external magnetic fields, currents, trapped flux

Approaches for improvement:

1. Moat design
2. Phase-shift devices
3. “Inductorless” circuits with small mutual inductances

Phase Engineering: φ Junctions

One Junction to rule them all?

- Storing element compaction [1]

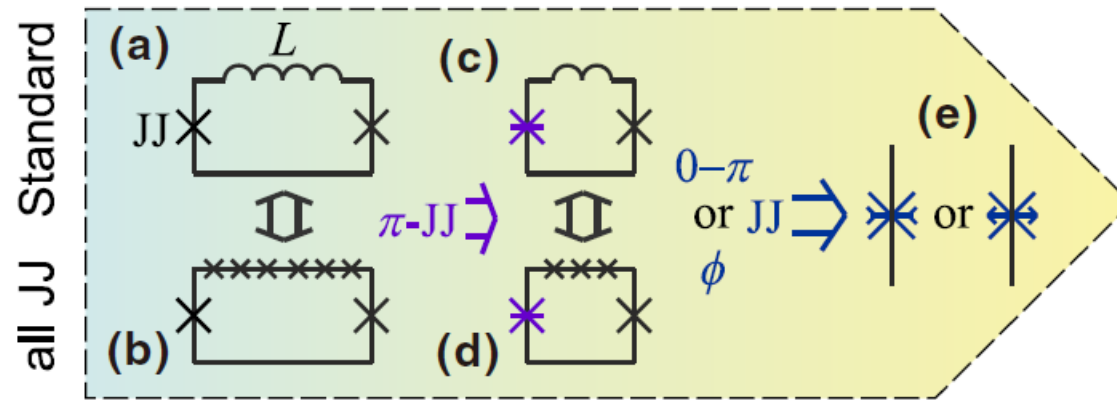


Fig. 1

- Question:
 - Can the devices be made?

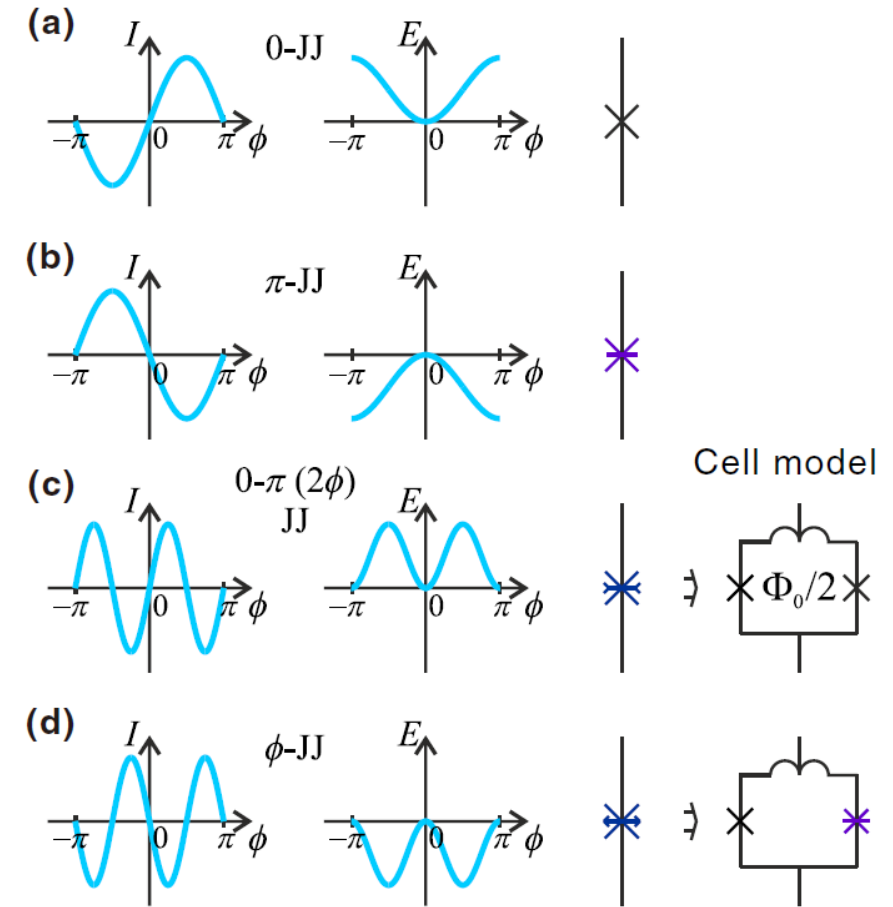


Fig. 2

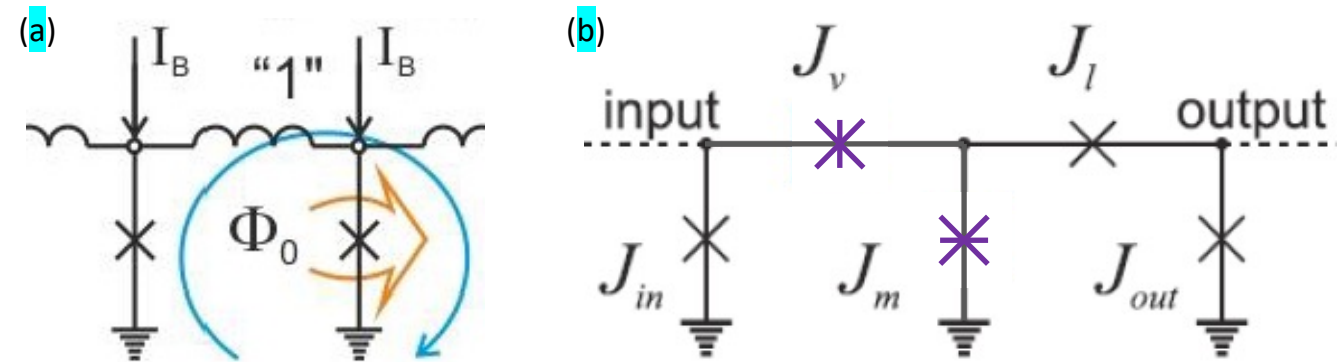
[1] I. I. Soloviev, "Superconducting circuits without inductors based on bistable Josephson junctions," 2021, doi: [10.1103/PhysRevApplied.16.014052](https://doi.org/10.1103/PhysRevApplied.16.014052)

“Inductorless” circuits with small mutual inductances



Non-traditional Josephson junctions to replace inductors, reduce JJ count

- Junction types
 - 0 junctions (SIS), switching
 - **0 junction stacks** (SNsNsNS)
 - π junctions (SFS)
 - ϕ junctions [1], [3]
- Questions:
 - Can the devices be made?
 - And with sufficiently small parameter variations (I_c , L)?



[1] (a) JTL with inductors, (b) JTL with magnetic junctions

[1] Soloviev +, “Superconducting circuits without inductors based on bistable Josephson junctions,” 2021, doi: [10.1103/PhysRevApplied.16.014052](https://doi.org/10.1103/PhysRevApplied.16.014052).
[2] Maksimovskaya +, “Phase logic based on π Josephson junctions,” 2022, doi: [10.1134/S0021364022600884](https://doi.org/10.1134/S0021364022600884).
[3] Bakurskiy +, “Compact Josephson ϕ -junctions,” 2018, doi: [10.1007/978-3-319-90481-8_3](https://doi.org/10.1007/978-3-319-90481-8_3).



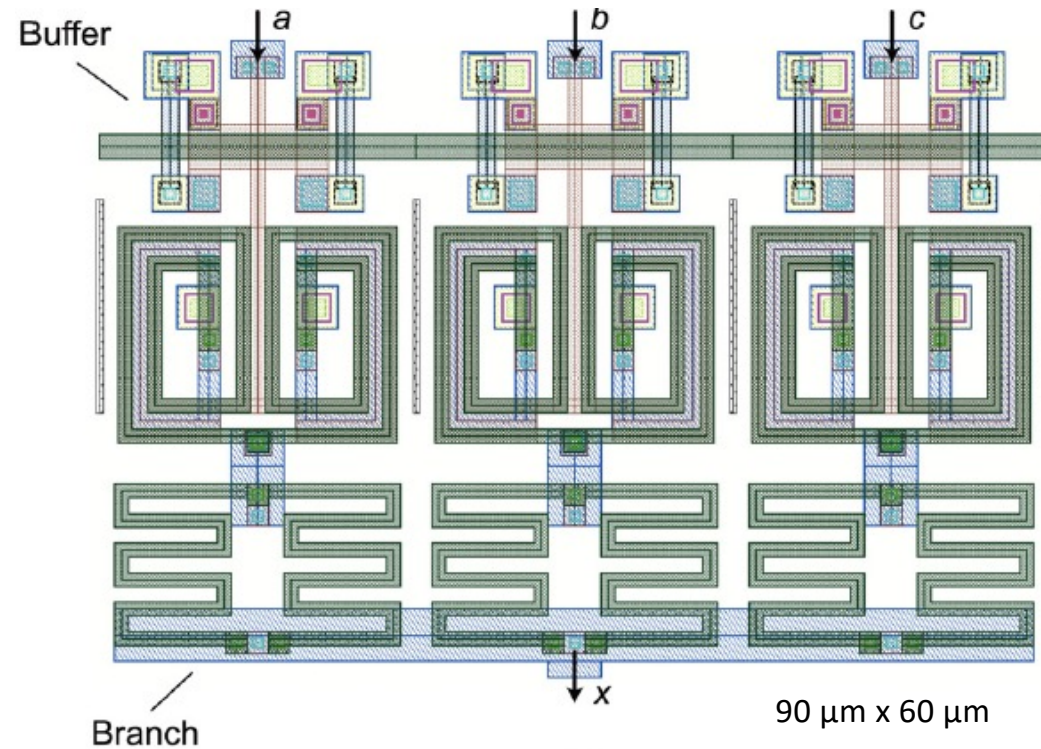
3. Area Reduction

Approaches for improvement:

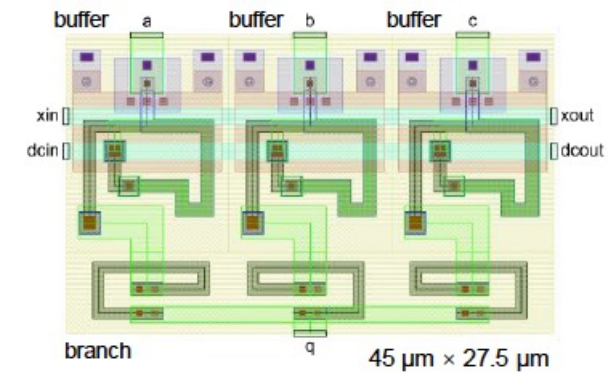
1. Inductors
2. Transformers (miniaturization, replacement, or avoidance)
3. Passive transmission lines (PTL)
4. Josephson junction (JJ) size reduction



Gate set example: AQFP (MAJ+INV)



(Output inversion takes no additional area)



Takeuchi+, **2015**, doi: [10.1063/1.4919838](https://doi.org/10.1063/1.4919838)

- AIST STP2 process
- M = F = 1500 nm
- 4 Nb layers, 1 JJ layer
- Jc = 25 MA/m²
- Area = 5400 μm²

$$\frac{1238}{5400} = 0.23 \sim 1/4$$

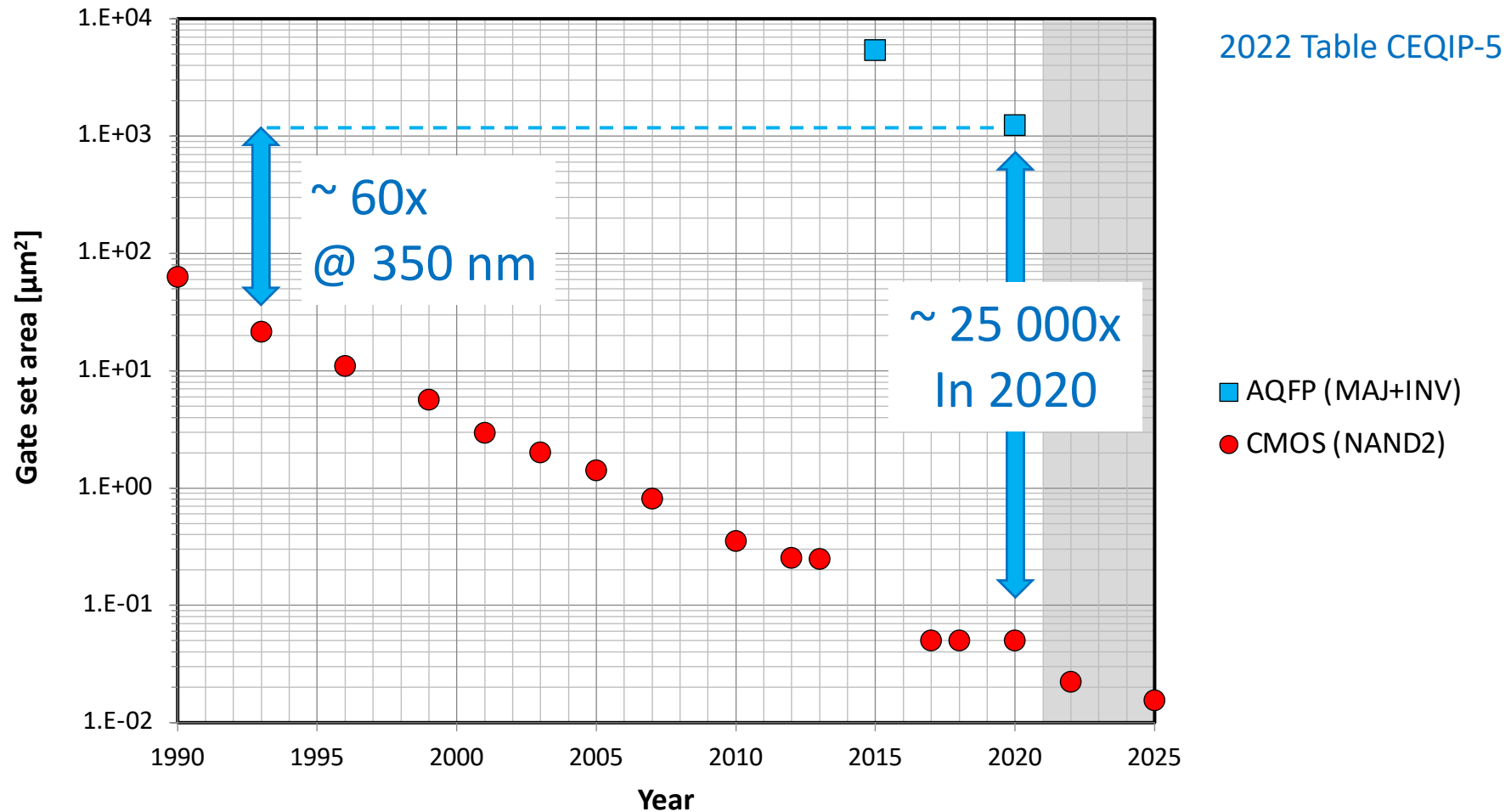


He+, **2020**, doi: [10.1088/1361-6668/ab6feb](https://doi.org/10.1088/1361-6668/ab6feb)

- MIT-LL SFQ5ee process
- M = F = 350 nm
- 8 Nb layers, 1 JJ layer
- Jc = 100 MA/m²
- Area = 1238 μm²



Gate Set Area: Comparison with CMOS

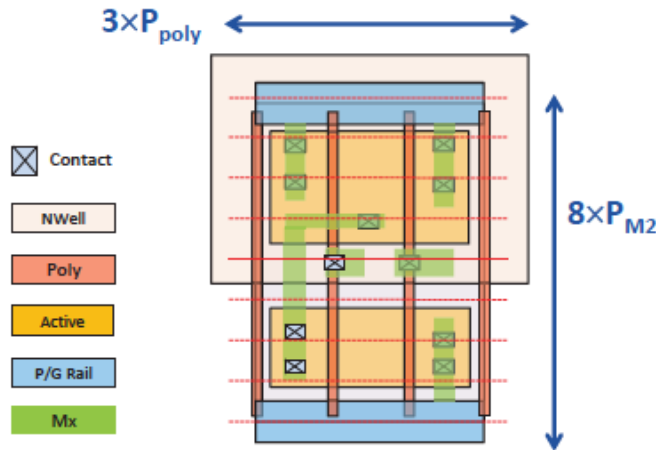


► Why is SCE logic area so much larger? (= lower density)

Gate sets: CMOS (NAND2) vs AQFP (MAJ+INV)



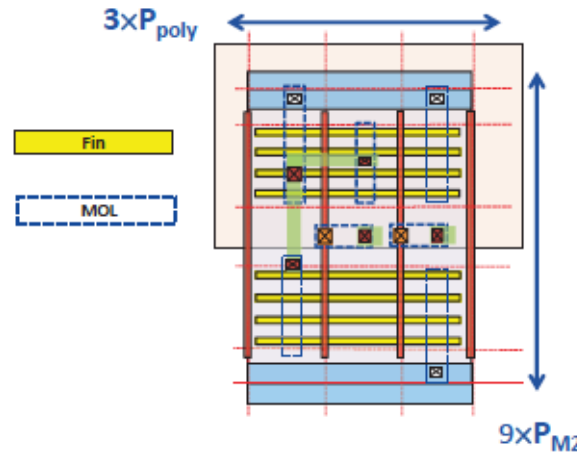
NAND2
(4 bulk planar FETs, 2011)



$$U_{logic} = 3P_{poly} \times 8P_{M2} = 180F^2$$

calibrated → 175F²

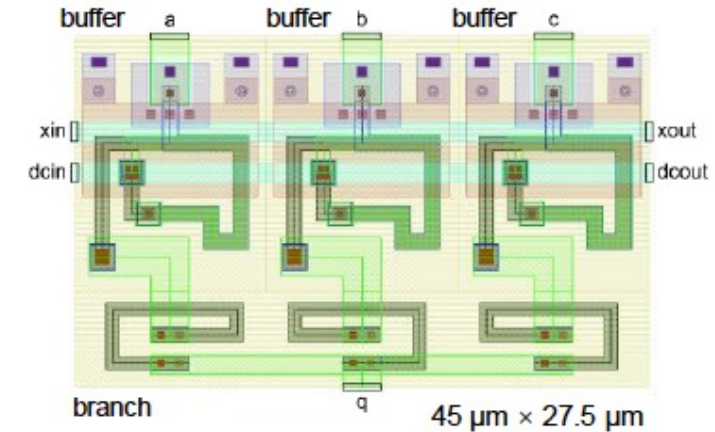
NAND2
(4 FINFETs, 2013)



$$U_{logic} = 3P_{poly} \times 9P_{M2} = 162F^2$$

calibrated → 155F²

MAJ+INV
(6 JJs, 2020)



He+, 2020, doi: [10.1088/1361-6668/ab6feb](https://doi.org/10.1088/1361-6668/ab6feb)

- MIT-LL SFQ5ee process, M = F = 350 nm
- MAJ area = 1238 μm² = 1238/(0.35)² = 10,106 F²

Chan+, 2014, doi: [10.1109/ICCD.2014.6974675](https://doi.org/10.1109/ICCD.2014.6974675)

- NAND2 area (bulk FET, ITRS 2011) = 175 F²
- NAND2 area (FINFET, ITRS 2013) = 155 F²

10,106/175
= 58

▶ Need to reduce the factor of ~ 60

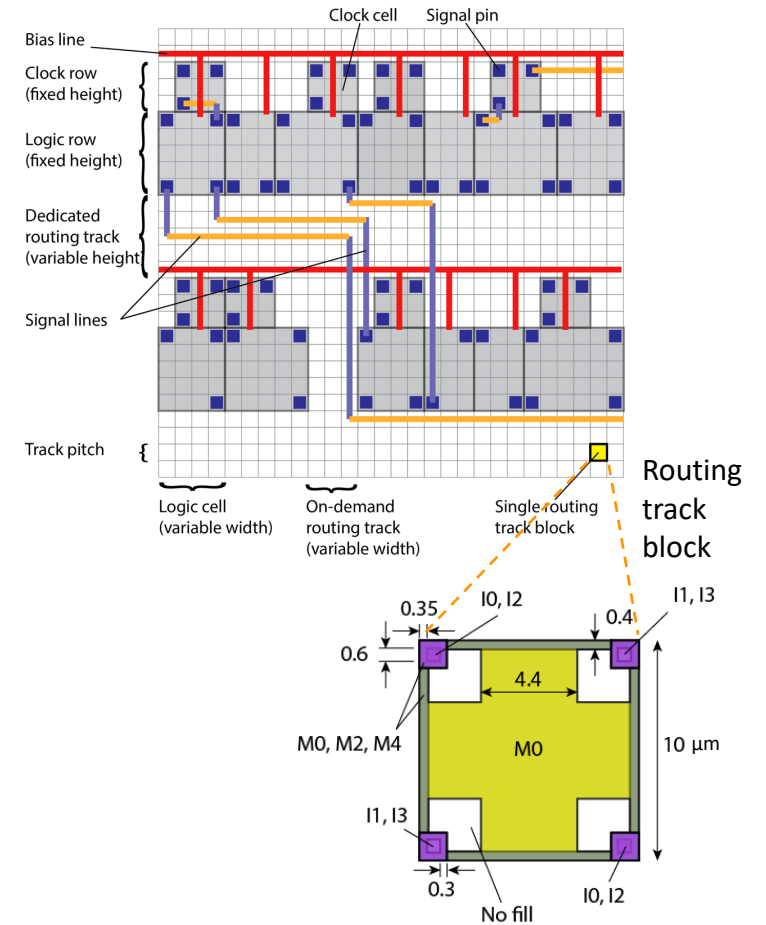
Circuit area reduction

SCE approaches

- Wiring layers: increase 8 → 10 → ?
- Inductor size
 - Decrease wire width or thickness
 - Use multiple wiring layers
 - Increase JJ current I_c (but $E_{switch} \propto I_c$)
 - High kinetic inductance layers
 - JJ stack inductors?
 - Transformers don't scale well (Tolpygo, 2022, [arXiv:2210.02632](https://arxiv.org/abs/2210.02632))

▶ ASC 2022 Oct 25 14:15, 2EPo2F-01, Tolpygo

- JJ size
 - Area $\propto 1/J_c$
 - No shunt resistor needed if $J_c \gtrsim 500 \mu\text{A}/\mu\text{m}^2$
 - Multiple JJ layers
 - Device options?



Row-based place-and-route architecture for RSFQ
Fourie+, 2020, doi: [10.1109/TASC.2020.2988876](https://doi.org/10.1109/TASC.2020.2988876)

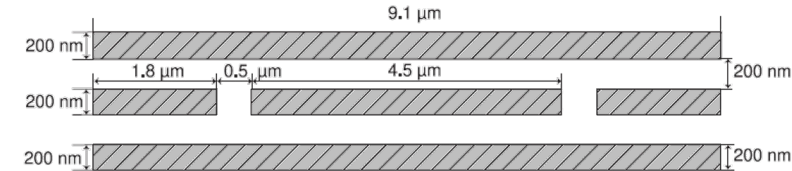
▶ Needed: models to guide roadmapping

Passive transmission lines (PTL)



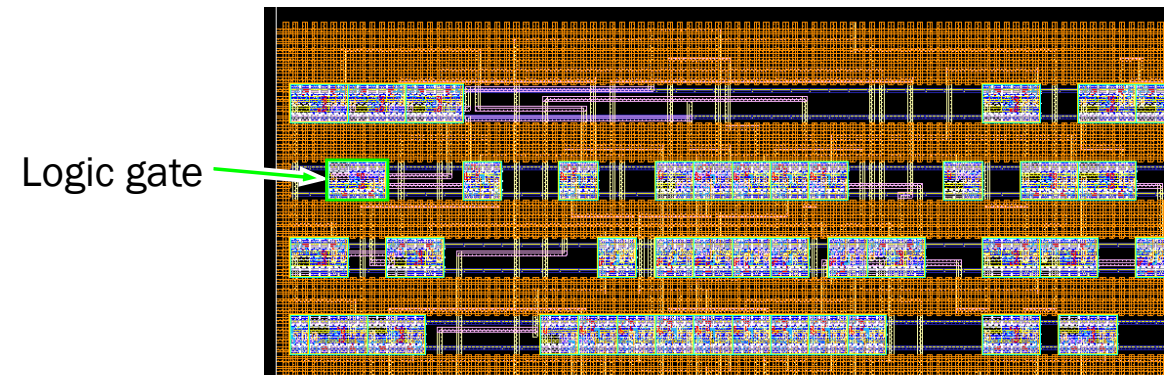
Important interconnects

- PTL width ($\sim 4 \mu\text{m}$) is a major obstacle to scaling
 - JJs are low impedance drivers
 - Reducing the PTL width increases impedance, which causes reflections due to impedance mismatch
 - Reducing JJ I_c increases impedance, but reduces pulse energy
- Using only PTLs for routing requires too much area
- Additional PTL layers would increase area density but require +2 metal layers each



PTL cross section

Herbst +, 2020, doi: [10.1109/TASC.2020.3006988](https://doi.org/10.1109/TASC.2020.3006988)



AMD2901 4-bit processor design with 16,840 gates (upper left portion of overall layout)

Placed and routed in Synopsys **Fusion Compiler (FC)** and viewed in Custom Compiler



4. Logic



Approaches for improvement:

1. AC clocking
2. Clock reduction or elimination
3. Data representation
4. Phase-shift devices
5. Macro blocks or cell-abutment logic
6. Neuromorphic Circuits
7. Quantum phase-slip junctions (QPSJ)
8. Multi-terminal (3+) switching devices



Superconductor Digital Logic Families

2022 Summary of current status

| Name | SFQ | Power | Static Power | Dynamic power per switch | Transformers | Clocked Gates | JJ count $\log_{10}(n)$ |
|---|-----|-------|--------------|---|--------------|---------------|-------------------------|
| RSFQ: rapid single flux quantum | 1 | - DC | High | $\alpha I_c \Phi_0 f$ | - | Yes | 4.4 |
| LR-RSFQ: inductor-resistor RSFQ | 1 | - DC | Low | $\alpha I_c \Phi_0 f$ | - | Yes | 1.6 |
| LV-RSFQ: low-voltage RSFQ | 1 | - DC | Low | $\alpha I_c \Phi_0 f$ | - | Yes | 3.7 |
| ERSFQ: energy-efficient RSFQ | 1 | - DC | 0 * | $I_b \Phi_0 f$ | - | Yes | 3.8 |
| eSFQ: efficient SFQ | 1 | - DC | 0 * | $I_b \Phi_0 f$ | - | Yes | 3.4 |
| Clockless SFQ | 1 | - DC | | | | | 2.8 |
| DSFQ: dynamic SFQ | 1 | - DC | ‡ | ‡ | - | Some | 0.7 |
| TSFQ: temporal SFQ | 1 | - DC | | | - | No | (2.8) |
| xSFQ: alternating SFQ | 2 | - DC | ‡ | ‡ | - | No | |
| nTron: nanowire cryotron | 1 | - DC | ~0 | varies | - | Yes | 1.5 |
| hTron: heater-cryotron nanowire | 1 | - DC | ~0 | varies | - | Yes | 1.2 |
| HFQ: half flux quantum | 0.5 | - DC | Low | | - | Yes | 1.2 |
| SFQ-AC: AC-powered SFQ | 1 | ~ AC | ‡ | ‡ | P | Yes | 5.9 |
| RQL: reciprocal quantum logic | 2 | ~ AC | ~0 | $\alpha I_c \Phi_0 f 2/3$ | P, G | Some | 4.9 |
| PML: phase mode logic | 1 | ~ AC | ~0 | $\alpha I_c \Phi_0 f /3$ | P, G | Some | |
| AQFP: adiabatic quantum flux parametron | - | ~ AC | ~0 | $\alpha I_c \Phi_0 2f \tau_{sw} / \tau_x$ | P, G | Yes | 4.3 |
| RQFP: reversible QFP | - | ~ AC | ~0 | $\alpha I_c \Phi_0 2f \tau_{sw} / \tau_x$ | P, G | Yes | 1.4 |

Other metrics?

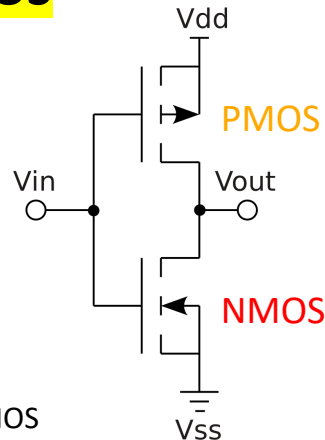
- Area
- Current
- Logic depth
- JJ per gate
- Scalability



Searching for a winning combination

Semiconductor logic families

| <u>1960s</u> | <u>1980s</u> |
|--------------|--------------|
| ECL | ECL |
| DTL | DTL |
| TTL | TTL |
| NMOS | NMOS |
| PMOS | PMOS |
| CMOS | CMOS |



en.wikipedia.org/wiki/CMOS

Superconductor logic families

| <u>2010s</u> | <u>2030s</u> |
|--------------|--------------|
| – RSFQ | |
| – ERSFQ | |
| – eSFQ | |
| – DSFQ | |
| – HFQ | |
| – nTron | |
| – xSFQ | |
| ~ SFQ-AC | |
| ~ RQL | |
| ~ PML | |
| ~ PCL | |
| ~ AQFP | |
| ~ DQFP | |
| ~ RQFP | |



Considerations:

- Performance
- Power
 - Static
 - Dynamic
 - Supply
- Cost
 - Ease of design
 - Area
 - Fabrication process
 - Yield
 - Shielding
- Compatibility
- ...



AC Clocking

Use AC power as the clock

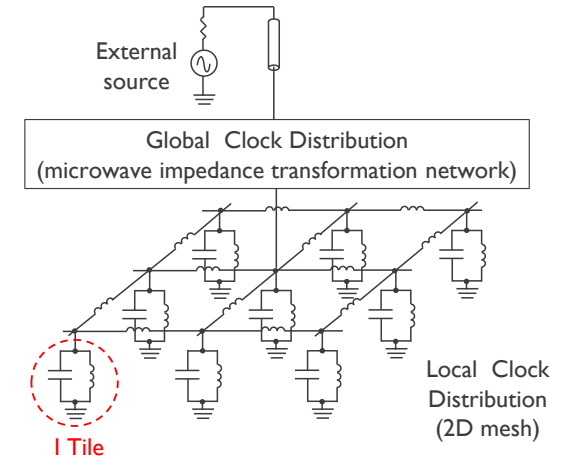
- AQFP (most established)
 - **Advantages:** JJs are all the same size and small (50 μA), energy efficient, good margins, majority logic
 - **Disadvantages:** large area, transformers, clocked gates, memory (?), majority logic
- Reciprocal quantum logic (RQL)
 - **Advantages:** Few JJs per logic gate, good margins, proven
 - **Disadvantages:** transformers, clock frequency limits, EDA tool support (?), controlled by Northrop Grumman
- **Pulse conserving logic (PCL)**
 - 12 levels of logic at 30 GHz
 - OMA3 gate (OR3/MAJ3/AND3)



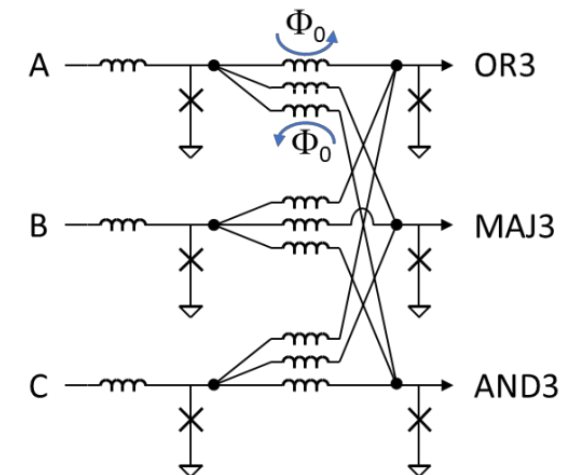
▶ ASC 2022 Oct 25 14:15, 2EPo2F-06 [E40], T. Josephsen

Design concept for large scale clock distribution 2D array of tightly coupled local, lumped LC resonators

- Local storage of power and clock signal in high-Q LC-resonators
 - 1 resonator/tile (1 tile $\sim 5 \times 5 \mu\text{m}^2$)
- 2D mesh of LC resonators has a zero-order mode
 - Clock signal distribution over large area with only small amplitude and phase variation
- 30 GHz design with 400 M taps/cm²



▶ ASC 2022 Oct 26 14:30, 3EPo2B-06 [E11], Q. Herr



Clock Reduction or Elimination

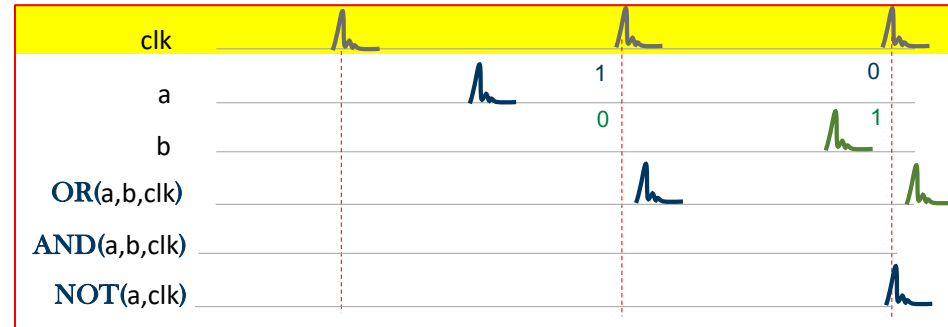


Overhead multiplies the cost of clocking!

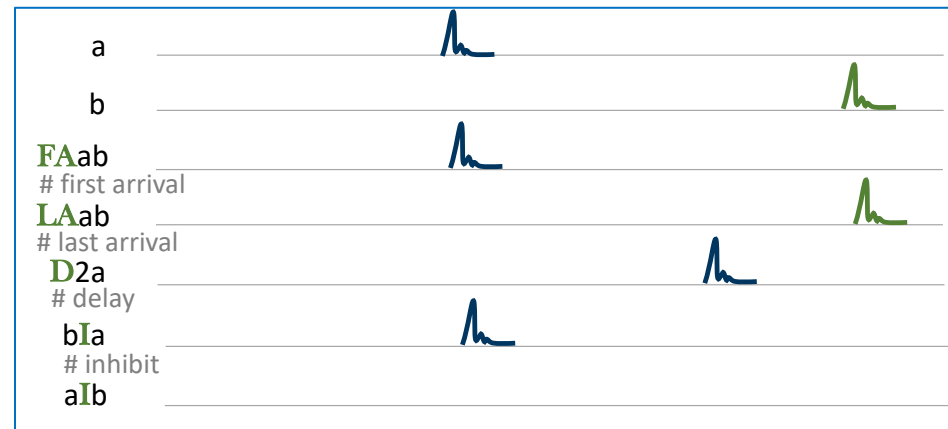
- Bias current overhead estimates **per clocked gate**:
 - ≈ 1.5× (?) for clocking (splitters, mostly)
 - ≈ 4× (?) for path balancing (superlinear)
 - ≈ 20× (?) for unused clock time (allowing for jitter, long lines, pipeline hazards, etc.)
 - ≈ 1.5× (?) for higher fraction of JJs that switch
- ≈ 180× (?) total

▶ Reduce or eliminate clocked cells

Clocked SFQ [1]



Temporal SFQ [1]



[1] Volk, "Circuit Abstractions for Low-Cost Fan-Out," ISCA, 2022

[2] Tzimpragos +, 2020, doi: [10.1145/3373376.3378517](https://doi.org/10.1145/3373376.3378517)

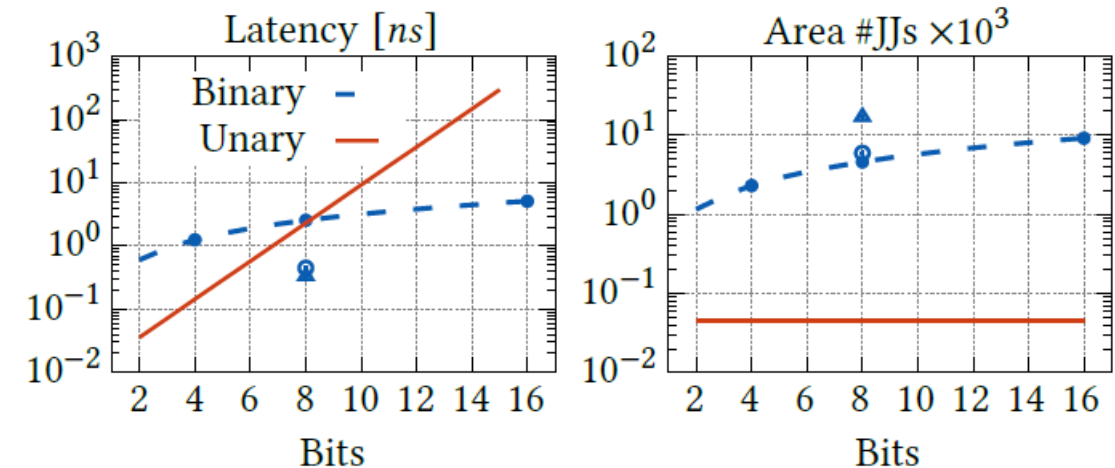
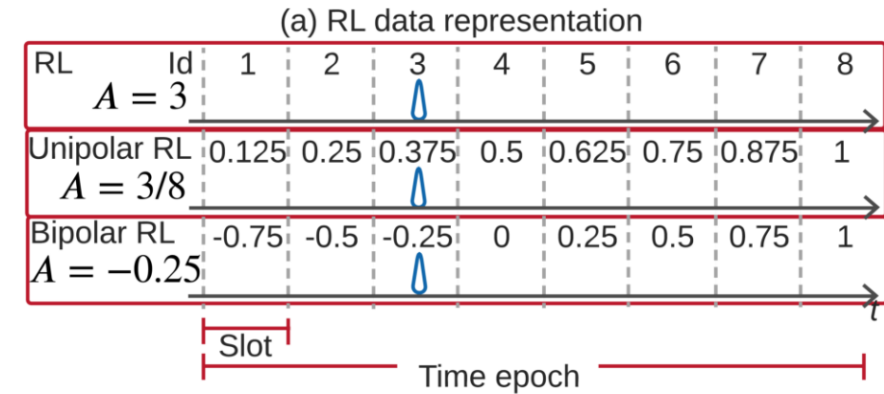
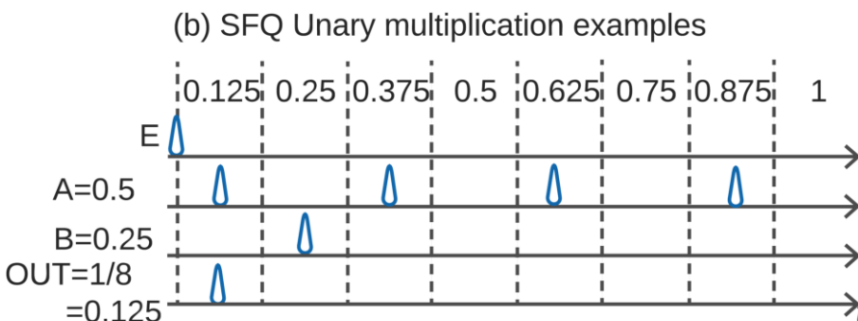
[3] Tzimpragos +, 2021, doi: [10.1109/ISCA52012.2021.00057](https://doi.org/10.1109/ISCA52012.2021.00057)



Data representation

“0” and “1” are not the only way

- Race logic (RL) represents data in time
- Time slots within a clock period can be used to represent information and perform computations
 - Unary SFQ is a combination of pulse-stream arithmetic and race logic
- Benefits can include greatly reduced circuit area

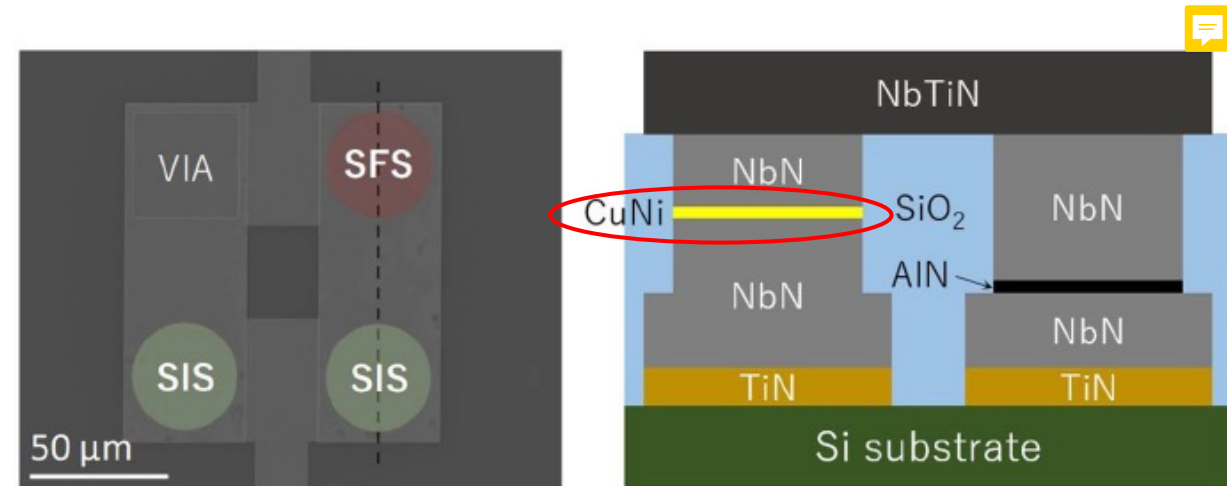


Multiplier circuit Latency and area comparison [1] Fig. 4

Pi Junctions

- Advantages
 - $\approx 10\times$ (?) reduction in supply current
 - Better margins
- Disadvantages
 - Area overhead factor $\approx \times 1.5$ (?)
 - Separate junction layer (adds cost)
 - Barrier material is different
 - **No polarity**: current goes either way!
- SCE roadmap
 - 2020 onwards
 - Ni only (change?)
 - Design tool support?
- Superconducting diode in series?

► Worth further development

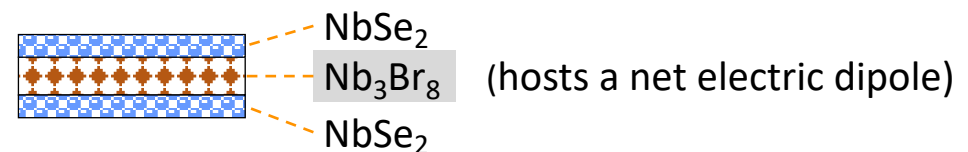


[1] Fig. 1. T_{dep} : 650 °C for TiN, < 100 °C for NbN, NbTiN

► pi-JJ (NbN/CuNi/NbN): $J_c = 629 \text{ MA/m}^2 (= \mu\text{A}/\mu\text{m}^2)$

[1] T. Yamashita +, “ π phase shifter based on NbN-based ferromagnetic Josephson junction on a silicon substrate,” 2020, doi: [10.1038/s41598-020-70766-9](https://doi.org/10.1038/s41598-020-70766-9).

Josephson diode: 2D quantum layers in the junction barrier

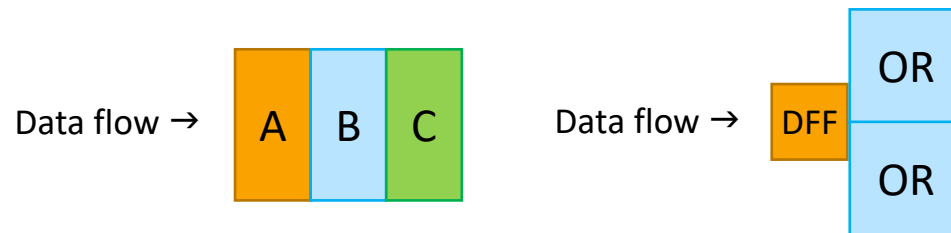


[2] H. Wu et al., “The field-free Josephson diode in a van der Waals heterostructure,” Nature, April 2022, doi: [10.1038/s41586-022-04504-8](https://doi.org/10.1038/s41586-022-04504-8).

[3] <https://www.tudelft.nl/en/2022/tnw/discovery-of-the-one-way-superconductor-thought-to-be-impossible>

Macro blocks or cell-abutment logic

- **Macro blocks** to perform complex functions
 - Smaller, better performance
 - Licensed as intellectual property (IP) blocks
 - We need more of these!
- **Cell abutment logic**
 - Cells connect directly, like LEGO blocks
 - Blocks can contain JTLs or PTLs
 - Problem: EDA tools do not currently support abutment

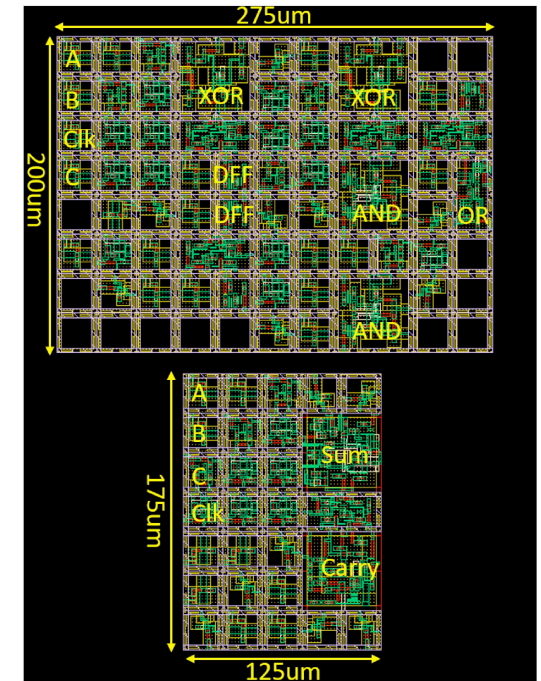


Volk +, 2022, [arXiv:2206.07817](https://arxiv.org/abs/2206.07817)

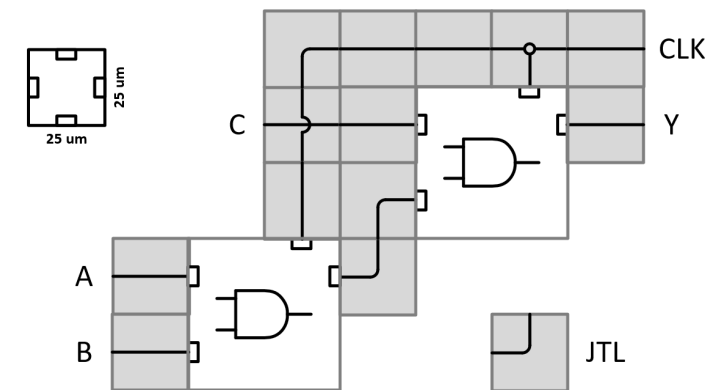
▶ ASC 2022 Oct 24 14:15, **1EPo2E-05 [E-38]**, Volk

2.5x area reduction: 8-bit multipliers using standard RSFQ gates and single-stage complex RSFQ gates

Cong +, 2021, doi: [10.1109/TASC.2021.3091963](https://doi.org/10.1109/TASC.2021.3091963)



Cell abutment strategy



▶ ASC 2022 Oct 26 14:30, **3EPo2B-05 [E-10]**, Cong

Neuromorphic Circuits using Superconductor Electronics



A more natural fit?

- Characteristics
 - Natural spiking behavior of Josephson junctions
 - Pulses travel on striplines without the RC time constants that typically hinder spike-based computing
 - Possibly tolerant to variations in component parameter values
- Needed:
 - Design methodology
 - Demonstrations at larger scale

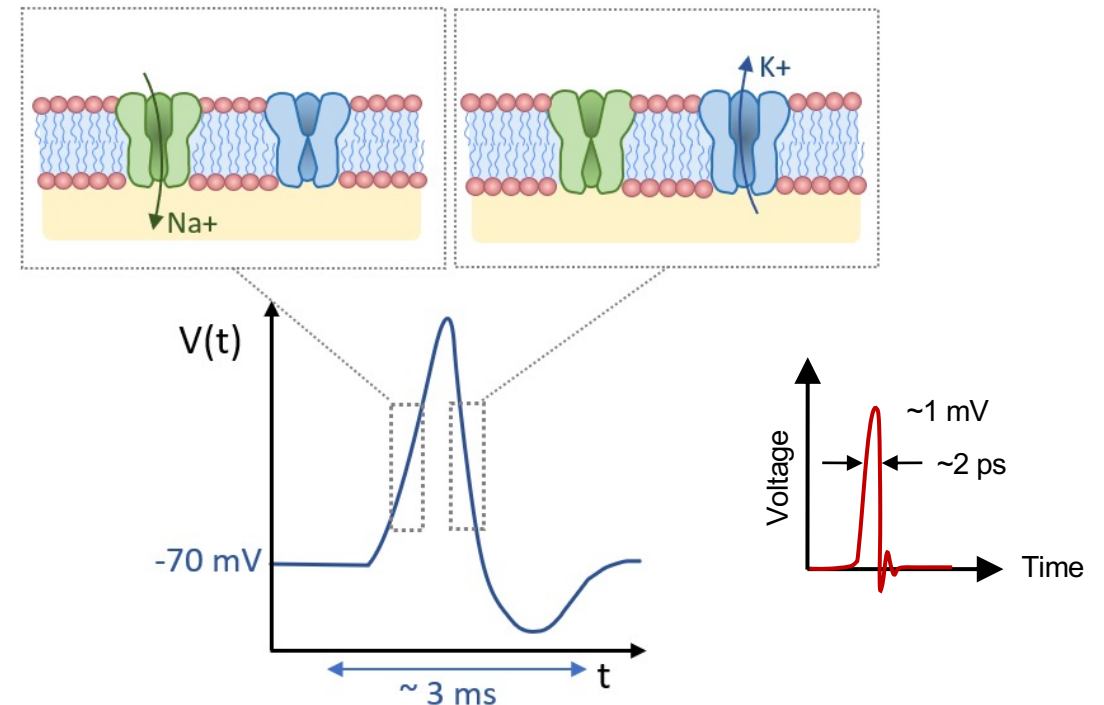


Fig. 3a. Spiking in biological neurons [1]

[1] Schneider +, “**Supermind**: a survey of the potential of superconducting electronics for neuromorphic computing,” 2022, doi: [10.1088/1361-6668/ac4cd2](https://doi.org/10.1088/1361-6668/ac4cd2)



▶ ASC 2022 Oct 26 17:00, **3EOr2C-02**, Primavera
“Superconducting optoelectronic single-photon synapses”

Quantum phase-slip junctions (QPSJs)

Voltage controlled devices might interface better with semiconductor electronics

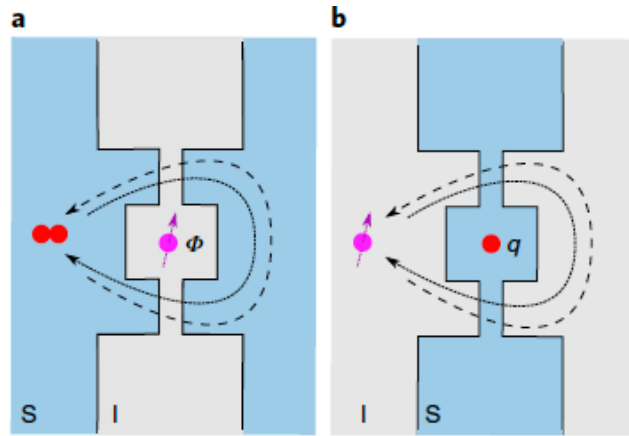
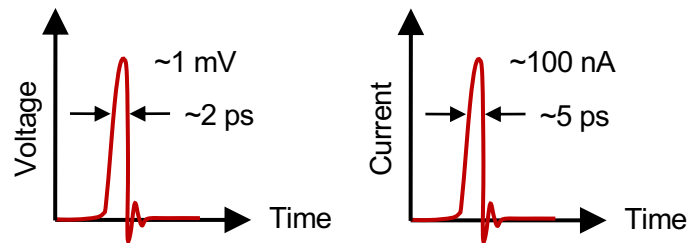


Fig. 1. SQUIDs using (a) JJJs, (b) QPSJs [1]



Single Flux Quantum (SFQ)
 $\Phi_0 = I \cdot L = \int V \cdot dt$

Cooper pair of electrons
 $2e = C \cdot V = \int I \cdot dt$

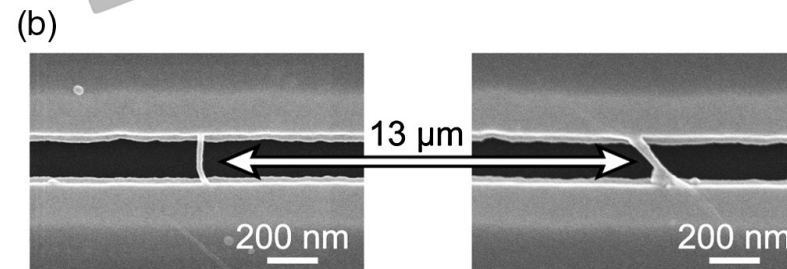
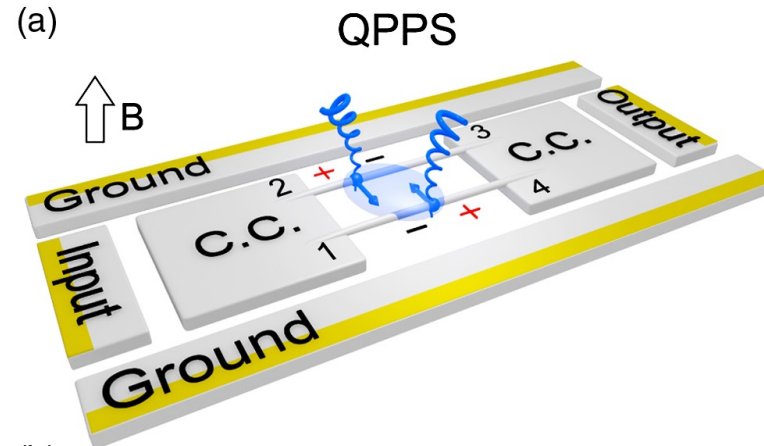


Fig. 2. MoGe nanowire QPSJs [2]

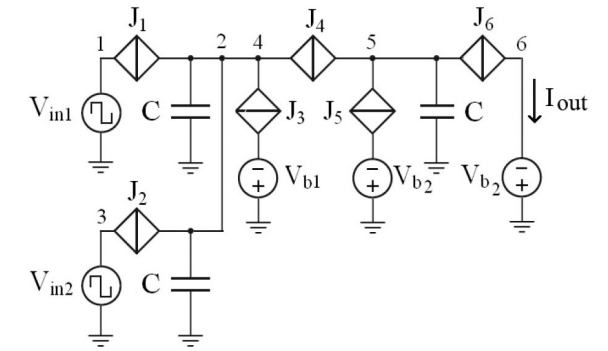


Fig. 3. Memoryless OR gate [3]

► **Demonstration needed!**

[1] de Graaf +, 2018, doi: [10.1038/s41567-018-0097-9](https://doi.org/10.1038/s41567-018-0097-9)

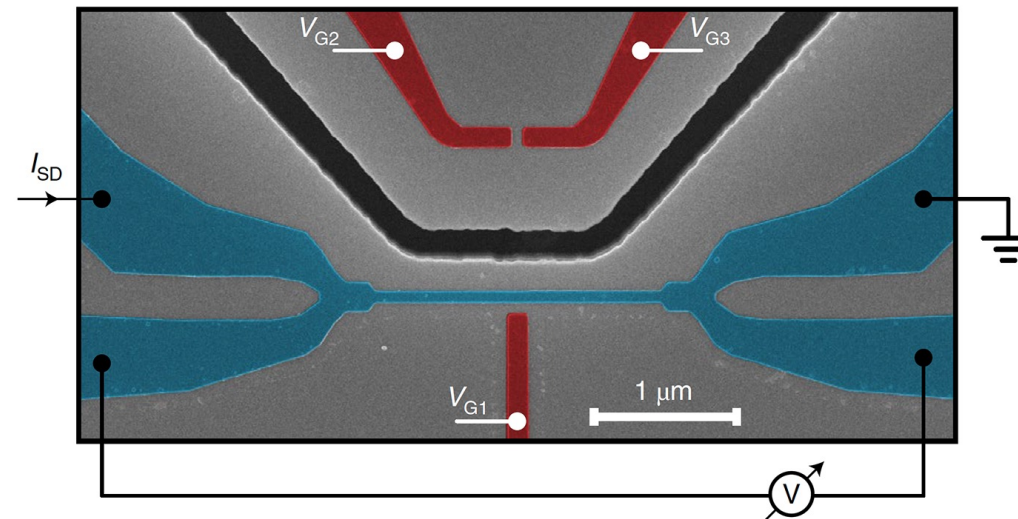
[2] Belkin +, 2015, doi: [10.1103/PhysRevX.5.021023](https://doi.org/10.1103/PhysRevX.5.021023)

[3] Malekpoor +, 2021, doi: [10.1109/TASC.2021.3121344](https://doi.org/10.1109/TASC.2021.3121344)

Multi-terminal (3+) switching devices

Gated superconducting nanowire device using... phonons!

- ▶ Electric field effect had been postulated
- ▶ Phonons now seem to be the cause
- ▶ What is the best way to generate and control phonons?



M. F. Ritter *et al.*, "Out-of-equilibrium phonons in gated superconducting switches," *Nat. Electron.*, vol. 5, Feb. 2022, doi: [10.1038/s41928-022-00721-1](https://doi.org/10.1038/s41928-022-00721-1).

5. Memory



Status

- Memory problems
 - Small memory capacity
 - Low area density
 - Addressing can add significant overhead
 - No commercial sources

Table CEQIP-6 Superconductor Memory Status (**demonstrated**)

| Name | RAM | Cell Size [μm^2] | Latency [ns] | | Energy [fJ] | | Static Power | Bits |
|---|-----|-------------------------------|--------------|-------|-------------|-------|--------------|---------|
| | | | Read | Write | Read | Write | | |
| SR: shift register, ac-biased | | 300 (15×20) | | | | | | 202 280 |
| SR: shift register | | | 0.02 | 0.02 | 0.1 | 0.1 | 0.2 mW | 1024 * |
| VTM: vortex transition memory | ✓ | 99 (9×11) | 0.10 | 0.10 | 100 | 100 | | 72 |
| JJ-RAM: Josephson junction RAM | ✓ | 484 (22×22) | | | | | 4.5 mW | 4096 |
| RQL-RAM : reciprocal quantum logic | ✓ | 1452 (33×44) | | | | | | 1024 |
| PRAM: PTL-RAM | ✓ | 1452 (33×44) | | | | | | 512 |
| SHE-MTJ: Spin Hall effect MTJ | ✓ | 2470 (38×65) | 0.10 | 2 | 1000 | 8000 | | 16 |
| SNM: superconducting nanowire mem. | ✓ | 26.5 (5×5.3) | 0.10 | 3 | 10 | 10 | | 8 |
| Hybrid: JJ-CMOS | ✓ | | 2 ~ 4 | 2 ~ 4 | 100 | 100 | | 65 536 |

* Incorrectly given as 64 in the 2022 report

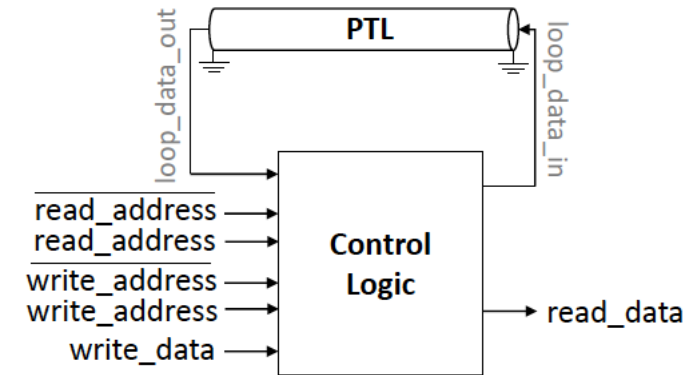
▶ A critical need!

Memory



Approaches for improvement (2):

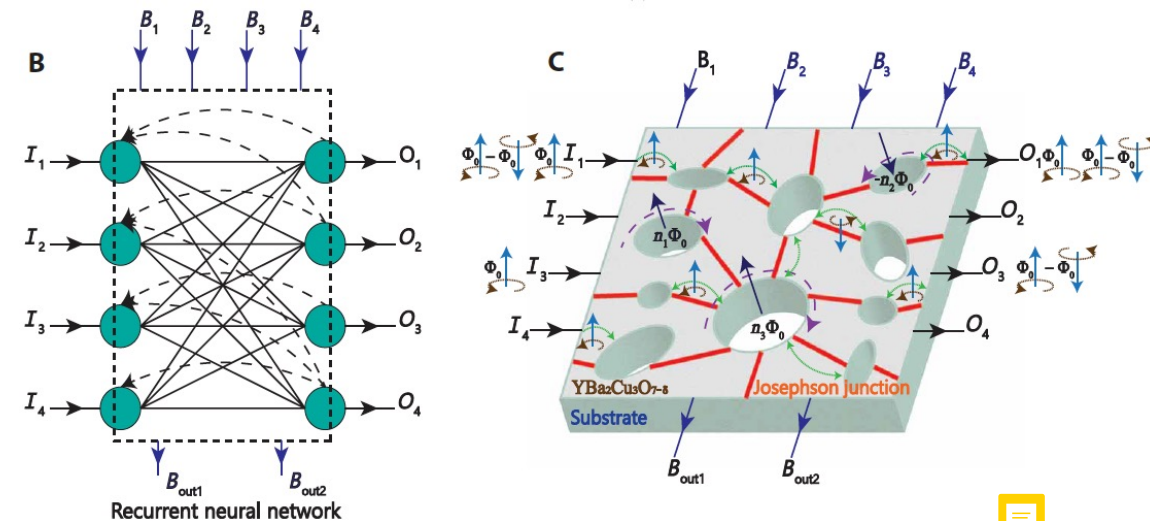
- Pulsar: A superconducting delay-line memory
 - Pulse velocity slows down in high-inductance PTLs, allowing higher memory density
 - NbN or NbTiN are candidate PTL materials
 - Control using temporal logic seems simpler than addressing logic for array-based RAM



PTL-based superconducting delay line memory system
Tzimpragos +, 2022, [arXiv:2205.08016](https://arxiv.org/abs/2205.08016)

- Loop memory
 - Superconducting disordered loop neural networks
 - He-ion beam defined JJs between holes in YBCO film
 - Memory states are affected by input signals or applied currents

▶ ASC 2022 Oct 25 16:15, 2EOr2B-08, Goteti



Goteti +, 2022, doi: [10.1126/sciadv.abn4485](https://doi.org/10.1126/sciadv.abn4485)



6. Fabrication for scale

Approaches for improvement:

1. Josephson junctions with reduced variation
2. Phase-shift devices *
3. NbN or NbTiN
4. Processing temperature compatible with CMOS BEOL (400 °C)
5. Multi-terminal (3+) switching devices *

* Covered earlier

Roadmap: Fabrication for Superconductor Electronics (SCE)



| Year | 2019 | 2020 | 2021 | 2022 | 2023 | 2024 | 2025 | 2026 | 2027 | 2028 | 2029 | 2030 | 2031 | 2032 | 2033 |
|---|----------|-----------|-----------|----------|----------|----------|----------|----------|----------|----------|----------|----------|----------|----------|----------|
| Digital SCE Fabrication | | | | | | | | | | | | | | | |
| "Node Range" label (nm) | "250" | "250" | "250" | "150" | "150" | "150" | "150" | "90" | "90" | "90" | "90" | "65" | "65" | "65" | "65" |
| Substrate material, maximum size (mm) | Si, 200 | Si, 200 | Si, 200 | Si, 200 | Si, 200 | Si, 200 | Si, 200 | Si, 300 | Si, 300 | Si, 300 | Si, 300 | Si, 300 | Si, 300 | Si, 300 | Si, 300 |
| Wiring | | | | | | | | | | | | | | | |
| Superconductor | Nb | Nb | Nb | Nb | Nb | Nb | Nb | Nb | Nb | Nb | Nb | Nb | Nb | Nb | Nb |
| Superconductor layers | 8 | 8 | 8 | 10 | 10 | 10 | 10 | 12 | 12 | 12 | 12 | 14 | 14 | 14 | 14 |
| Linewidth, minimum (nm) | 250 | 250 | 250 | 150 | 150 | 150 | 150 | 90 | 90 | 90 | 90 | 65 | 65 | 65 | 65 |
| I _c , minimum (μA) | 200 | 200, 1200 | 200, 1200 | 100, 580 | 100, 580 | 100, 580 | 100, 580 | 50, 290 | 50, 290 | 50, 290 | 50, 290 | 20, 110 | 20, 110 | 20, 110 | 20, 110 |
| Junctions, Switching | | | | | | | | | | | | | | | |
| Junction materials | Al/AIOx | Al/AIOx | Al/AIOx | Al/AIOx | Al/AIOx | Al/AIOx | Al/AIOx | Al/AIOx | Al/AIOx | Al/AIOx | Al/AIOx | Al/AIOx | Al/AIOx | Al/AIOx | Al/AIOx |
| Junction layers | 1 | 2 | 2 | 2 | 2 | 2 | 2 | 2 | 2 | 2 | 2 | 2 | 2 | 2 | 2 |
| Junction critical current densities, J _c (μA/μm ²) | 100 | 100, 600 | 100, 600 | 100, 600 | 100, 600 | 100, 600 | 100, 600 | 100, 600 | 100, 600 | 100, 600 | 100, 600 | 100, 600 | 100, 600 | 100, 600 | 100, 600 |
| Minimum junction diameter (nm) | 500 | 500 | 500 | 350 | 350 | 350 | 350 | 250 | 250 | 250 | 250 | 250 | 150 | 150 | 150 |
| Minimum junction critical current, I _c (μA) | 20 | 20, 118 | 20, 118 | 10, 58 | 10, 58 | 10, 58 | 10, 58 | 5, 29 | 5, 29 | 5, 29 | 5, 29 | 5, 29 | 2, 11 | 2, 11 | 2, 11 |
| Killer defect density per layer (1/cm ²) | < 0.1 | < 0.1 | < 0.1 | < 0.1 | < 0.1 | < 0.1 | < 0.1 | < 0.1 | < 0.1 | < 0.1 | < 0.1 | < 0.1 | < 0.1 | < 0.1 | < 0.1 |
| J _c wafer-to-wafer variation | 10% | 3% | 3% | 3% | 3% | 3% | 3% | 3% | 3% | 3% | 3% | 3% | 3% | 3% | 3% |
| Maximum relative spread (σ/I _c) at minimum I _c | 3% | 3% | 3% | 3% | 3% | 3% | 3% | 3% | 3% | 3% | 3% | 3% | 3% | 3% | 3% |
| Junctions, Magnetic (Pi) | | | | | | | | | | | | | | | |
| Junction materials | | Ni | Ni | Ni | Ni | Ni | Ni | Ni | Ni | Ni | Ni | Ni | Ni | Ni | Ni |
| Junction layers | 0 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 |
| Junction critical current densities (μA/μm ²) | | 3000 | 3000 | 3000 | 3000 | 3000 | 3000 | 3000 | 3000 | 3000 | 3000 | 3000 | 3000 | 3000 | 3000 |
| Junction diameter, minimum (nm) | 500 | 500 | 500 | 350 | 350 | 350 | 350 | 250 | 250 | 250 | 250 | 250 | 250 | 250 | 250 |
| Resistors | | | | | | | | | | | | | | | |
| Resistor material | Mo, MoNx | Mo, MoNx | Mo, MoNx | Mo, MoNx | Mo, MoNx | Mo, MoNx | Mo, MoNx | Mo, MoNx | Mo, MoNx | Mo, MoNx | Mo, MoNx | Mo, MoNx | Mo, MoNx | Mo, MoNx | Mo, MoNx |
| Resistor layers | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 |
| Resistor sheet resistance (Ω/□) | 2, 6, 10 | 2, 6, 10 | 2, 6, 10 | 2, 6, 10 | 2, 6, 10 | 2, 6, 10 | 2, 6, 10 | 2, 6, 10 | 2, 6, 10 | 2, 6, 10 | 2, 6, 10 | 2, 6, 10 | 2, 6, 10 | 2, 6, 10 | 2, 6, 10 |
| HKI (high kinetic inductance) Layers | | | | | | | | | | | | | | | |
| HKI material | MoNx | NbNx | NbNx | NbNx | NbNx | NbNx | NbNx | NbNx | NbNx | NbNx | NbNx | NbNx | NbNx | NbNx | NbNx |
| HKI layers | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 1 |





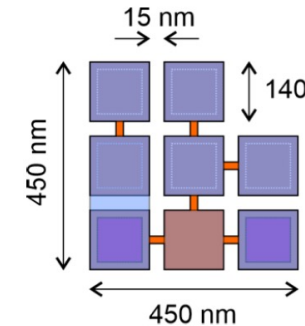
Junction scaling

Alternatives to the Nb/Al-AIO_x/Nb junction

- Semiconductor barriers
 - a-Si, a-SiNb_x [1]
- Nanobridges
 - Nanowire superconductor
 - SN-N-NS and SN-NF-SN junctions [2]-[4]



- Question:
 - Can the devices be made with sufficiently small parameter variations (I_c , L)?



[2] Notional D flip-flop layout using magnetic junctions instead of inductors.

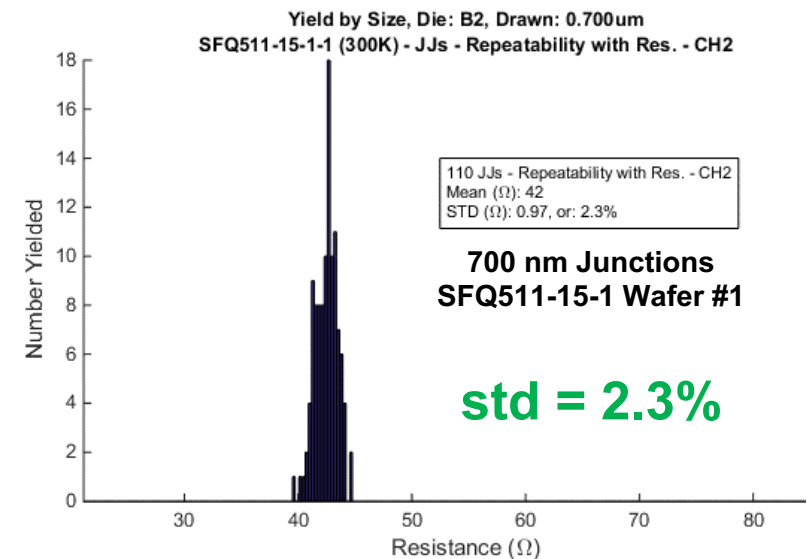
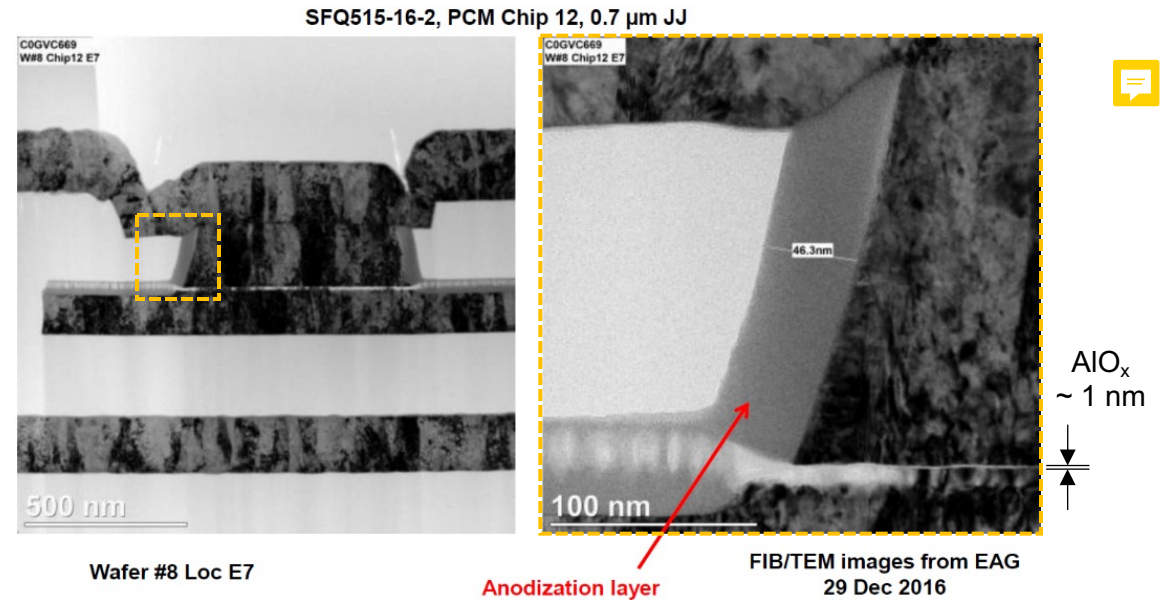
▶ ~ NAND2 area in 2012

[1] D. Olaya, "Nb/a-Si/Nb Josephson junctions for superconducting analog and digital electronics," ASC 2020, Wk1EO3B-02.
[2] I. I. Soloviev, "Superconducting digital circuits scaling pathway," ASC 2020, Wk2EO1B-07.
[3] I. I. Soloviev +, "Miniaturization of Josephson junctions for digital superconducting circuits," 2021, DOI: [10.1103/PhysRevApplied.16.044060](https://doi.org/10.1103/PhysRevApplied.16.044060).
[4] S. V. Bakurskiy et al., "Compact Josephson ϕ -junctions," 2018, DOI: [10.1007/978-3-319-90481-8_3](https://doi.org/10.1007/978-3-319-90481-8_3).

Junction scaling

Nb/Al-AIO_x/Nb Josephson junctions are almost good enough

- Nb
 - Columnar grain growth produces roughness, grain boundaries and cracking at via edges [1]
- AlO_x barriers formed by oxidation of Al:
 - Properties depend on oxidation conditions [2]
 - Variation increases for diameters smaller than ~ 500 nm, and critical current density $J_c > 100 \text{ MA/m}^2$ (thickness < 1 nm)
 - Temperature limits < 200 °C make gap fill difficult
- Anodization:
 - Stress on junction increases as junction radius decreases
 - Not scalable to 300 mm?
- Temperature: < 200 °C, CMOS BEOL: 400 °C

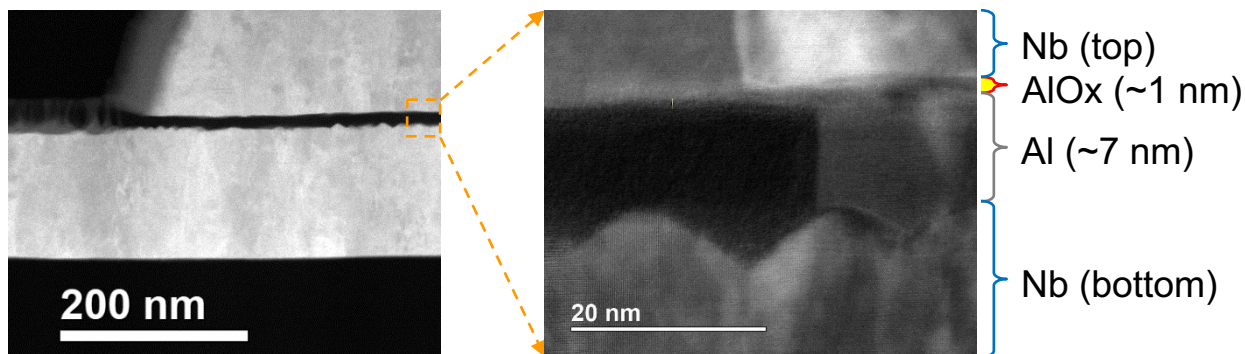


[1] N. Pokhrel, et al., “Modeling the effect of fabrication process on grain boundary formation in Nb/Al-AIO_x/Nb Josephson junction circuit,” *IEEE Trans. Appl. Supercond.*, Aug. 2021, doi: [10.1109/TASC.2021.3066533](https://doi.org/10.1109/TASC.2021.3066533).

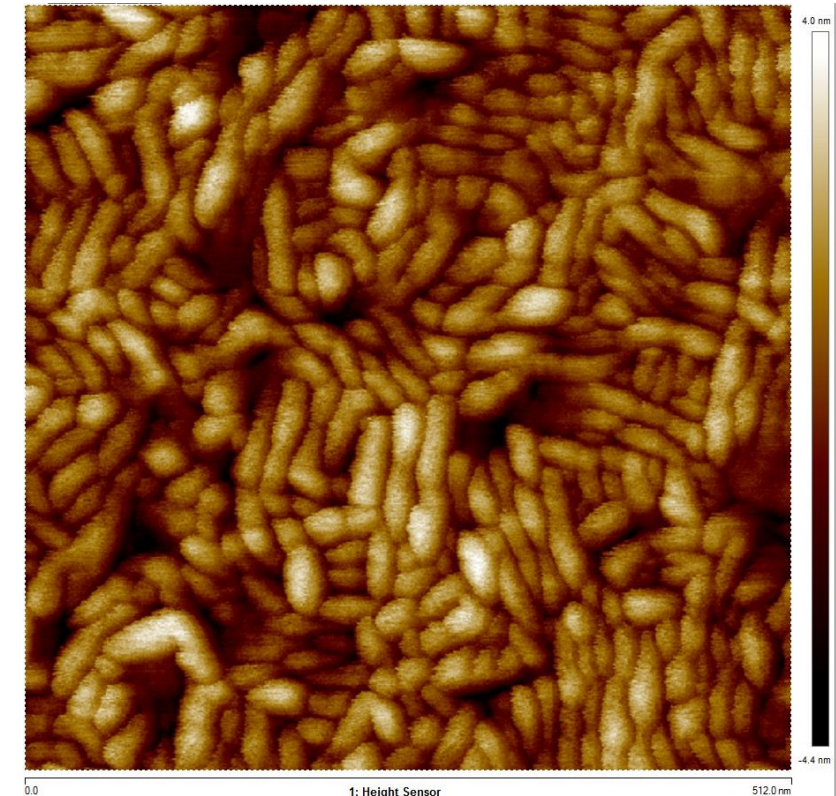
Surface roughness within a Josephson junction



- Roughness of the surfaces within a Josephson junction contributes to critical current variations
 - STEM pictures of cross sections previously provided by MITLL only gave a qualitative measure of the Nb and Nb+Al surface roughness below the ~ 1 nm thin AlOx layer in the junction.
 - TCAD process models need better information about the surface roughness.
- MITLL recently completed atomic force microscope (AFM) scans of surfaces at various stages of junction formation
 - Scans after: SiO2 underlayer polishing, Nb deposition, Al deposition
 - Fourier analysis on the scan data should allow better understanding and modeling of the surface roughness.



Josephson junction cross sections (side view)



AFM surface scan (512 nm x 512 nm) of a 150 nm thick niobium layer, 15 mm from the edge of a 200 mm diameter wafer

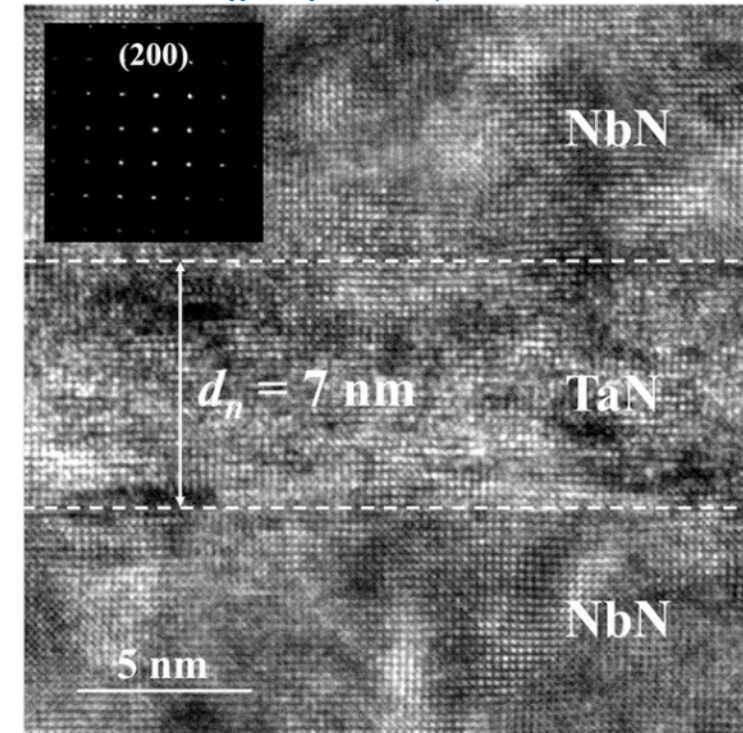
Image statistics:

| | |
|----------------|-----------------------------------|
| 0.96 nm | Ra (arithmetic roughness average) |
| 1.20 nm | Rq (rms surface roughness) |
| 9.16 nm | Z range |

NbN or NbTiN superconductor

A step up in critical temperature

- Nb
 - Critical temperature $T_C = 9.1 \text{ K}$
 - Processing temperature: $< 200 \text{ }^\circ\text{C}$; CMOS BEOL: $400 \text{ }^\circ\text{C}$
 - Columnar grain growth produces roughness, grain boundaries and cracking at via edges
- NbN or NbTiN
 - Critical temperature $T_C \approx 9\text{--}16 \text{ K}$ (10–100 nm thick)
 - Epitaxial growth on MgO or Si\TiN substrates by reactive sputter deposition from room temperature to $400 \text{ }^\circ\text{C}$
 - CVD or ALD deposition is possible
 - Smoother surface than Nb, less chemically reactive, less sensitive to oxygen contamination
 - High kinetic inductance
 - Josephson junction barriers: AlN, TaN_x, NbN_x [1-3]



[2] Figure 1b. **NbN** (200 nm)/**TaN** (7 nm)/**NbN** (200 nm) epitaxial trilayer fabricated on MgO

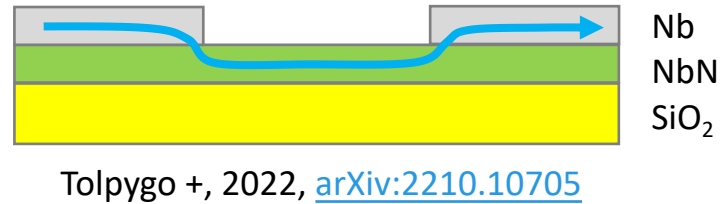
▶ $J_c = 1.08\text{--}1.43 \text{ GA/m}^2 (= \text{mA}/\mu\text{m}^2)$

- [1] Z. Wang *et al.*, “High-quality epitaxial NbN/AlN/NbN tunnel junctions with a wide range of current density,” *Appl. Phys. Lett.*, Apr. 2013, doi: [10.1063/1.4801972](https://doi.org/10.1063/1.4801972).
- [2] K. Yan *et al.*, “Intrinsically shunted Josephson junctions with high characteristic voltage based on epitaxial NbN/TaN/NbN trilayer,” *Appl. Phys. Lett.*, Oct. 2021, doi: [10.1063/5.0064733](https://doi.org/10.1063/5.0064733).
- [3] L. Zhang *et al.*, “Electrical properties of NbN/NbN_x/NbN Josephson junctions,” *Supercond. Sci. Technol.*, Dec. 2021, doi: [10.1088/1361-6668/ac2eaf](https://doi.org/10.1088/1361-6668/ac2eaf).

NbN or NbTiN fabrication processes

- **NbN/Nb bilayers**

- 2-step patterning process
- Current flows through lowest inductance path (Nb, if present)



- Process with planarized **NbN** layers (MITLL)

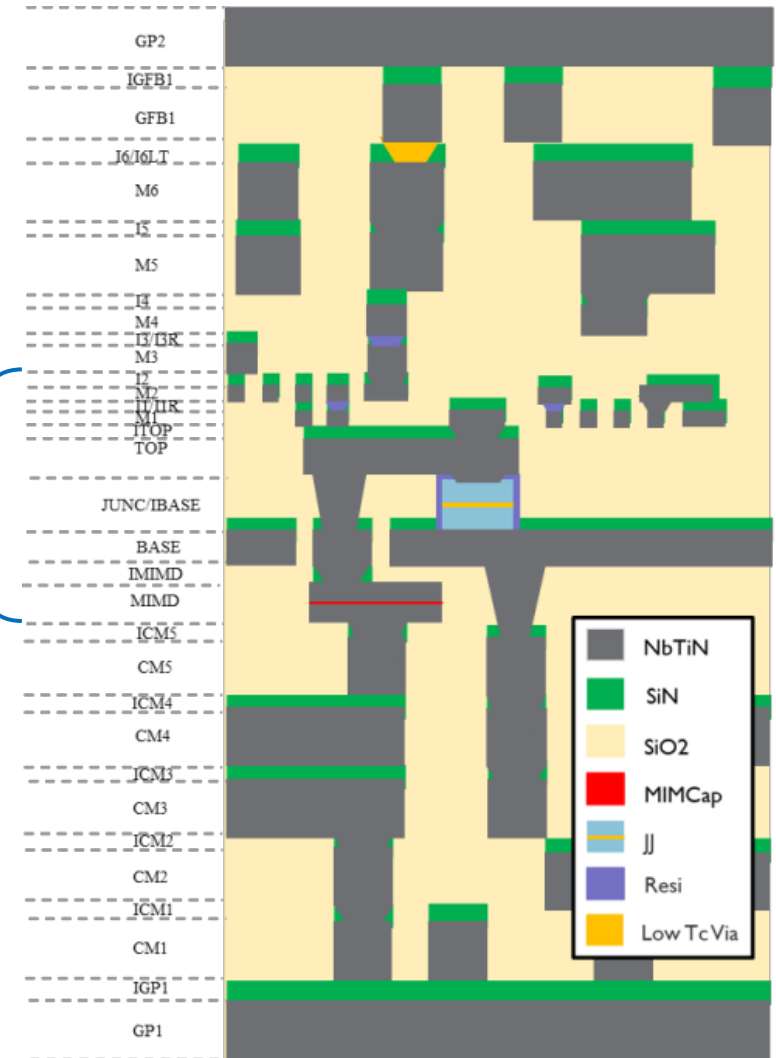
▶ ASC 2022 Oct 24 16:15, **1EOr2C-01**, Tolpygo

- **NbTiN** digital stack process (IMEC)

- $T_c = 11$ to 13 K
- NbTiN films can scale to 7.6 nm thickness
- 50 nm line widths demonstrated with $T_c = 12.5$ K and $I_c = 200 \mu\text{A}$

▶ ASC 2022 Oct 24 17:15, **1EOr2C-04**, A. Herr
“Scaling superconducting digital technology to 400M JJ/cm²”

In development



NbTiN digital stack process vision (IMEC)



Conclusions

Keys needs in the technology roadmap for superconductor electronics

1. Power distribution

- Biasing junctions using externally-supplied direct current (DC) does not scale!

2. Sensitivity to external magnetic fields, currents, and trapped flux

- Greatest improvements involve disruptive changes

3. Area reduction

- Many approaches, finding the best combination is the challenge

4. Logic

- Clocking every logic gate does not scale! Still searching for a winning combination.

5. Memory

- Greatest need for innovation!

6. Fabrication for scale

- Changes are costly and require consideration.

▶ Some solutions on the horizon, but plenty of room for innovation!

Catching the wave

Be ready!



References

1. “IRDS 2022: Cryogenic Electronics and Quantum Information Processing,” IEEE International Roadmap for Devices and Systems, 2022. <https://irds.ieee.org/editions/2022>
2. D. S. Holmes, “Superconductor electronic device technology roadmapping within the IRDS,” *IEEE Electron Devices Society Newsletter*, pp. 6–11, Apr. 2022. https://eds.ieee.org/images/files/newsletters/Newsletter_Apr22.pdf

TECHNICAL BRIEFS

SUPERCONDUCTOR ELECTRONIC DEVICE TECHNOLOGY ROADMAPPING WITHIN THE IRDS

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Abstract—For superconductor electronics to meet the needs expected for applications such as quantum computing or large-scale digital computing, significant improvements will be required, especially in circuit density and complexity. Key to improvement are innovations in superconductor devices and logic families. Technology roadmaps are under development to provide goals and timelines.

such as higher clock frequencies, faster data movement, and lower energy per computation. Neuromorphic computing for large-scale artificial intelligence applications needs energy-efficient solutions and might be a natural fit for superconductor circuits that naturally use pulse-based logic. Quantum computing using superconducting circuits requires operation at temperatures around 10 mK where the energy loss in semiconductor control and interface circuits seems prohibitive at full scale.

their present forms are unlikely to meet the expected future requirements. New devices, circuits, fabrication processes, and architectures are needed.

A full discussion of the applications, drivers, and technology ecosystem for superconductor electronics is not possible in this short article. For further information, see the latest available IRDS CEQIP report [1]. This article will focus on device developments needed for superconductor electronics.

Index Terms—superconductor elec-

II. Essentials of Superconductor